



中国认可
国际互认
检测
TESTING
CNAS L6478



TEST REPORT

Reference No. : WTF25F11291489W003
Applicant : Mid Ocean Brands B.V.
Address : Unit 711-716, 7/F., Tower A, 83 King Lam Street, Cheung Sha Wan, Kowloon, Hong Kong.
Manufacturer : 106613
Address : ---
Product Name : Wireless mouse in bamboo
Model No. : MO2085
Test specification : ETSI EN 301 489-1 V2.2.3 (2019-11)
ETSI EN 301 489-3 V2.3.2 (2023-01)
Date of Receipt sample : 2025-11-18
Date of Test : 2025-11-19 to 2025-11-25
Date of Issue : 2025-11-29
Test Report Form No. : WEW-301489A-01B
Test Result : **Pass**

Remarks:

The results shown in this test report refer only to the sample(s) tested, this test report cannot be reproduced, except in full, without prior written permission of the company. The report would be invalid without specific stamp of test institute and the signatures of approver.

Prepared By:

Waltek Testing Group (Foshan) Co., Ltd.

Address: 1/F., Building 19, Sunlink Machinery City, Xingye 4 Road,
Guanglong Industrial Park, Chihua Neighborhood Committee, Chencun,
Shunde District, Foshan, Guangdong, China

Tel: +86-757-23811398

Fax: +86-757-23811381

E-mail: info@waltek.com.cn

Tested by:

Approved by:

Roy Hong

Danny Zhou



1 Test Summary

Emission				
Test	Test Requirement	Test Method	Class / Severity	Result
Conducted Emissions	ETSI EN 301 489-3 V2.3.2	ETSI EN 301 489-1 V2.2.3 EN 55032	Table A.10 of EN 55032	Pass
Radiation Emission		ETSI EN 301 489-1 V2.2.3 EN 55032	Table A.4 and Table A.5 of EN 55032	Pass
Immunity				
Test	Test Requirement	Test Method	Class / Severity	Result
Electrostatic Discharge (ESD)	ETSI EN 301 489-3 V2.3.2	ETSI EN 301 489-1 V2.2.3 EN 61000-4-2	±2/±4 kV Contact ±2/±4/±8 kV Air	Pass
Radio frequency electromagnetic field (80 MHz to 6 000MHz)		ETSI EN 301 489-1 V2.2.3 EN 61000-4-3	3V/m, 80%, 1kHz, Amp. Mod.	Pass
Fast Transients Common Mode (EFT)		ETSI EN 301 489-1 V2.2.3 EN 61000-4-4	AC±0.5/1.0kV	Pass
Surge		ETSI EN 301 489-1 V2.2.3 EN 61000-4-5	±1kV D.M.† ±2kV C.M.‡	Pass
RF common mode 0,15 MHz to 80 MHz (CS)		ETSI EN 301 489-1 V2.2.3 EN 61000-4-6	3Vrms(emf), 80%, 1kHz Amp. Mod.	Pass
Voltage Dips and Interruptions		ETSI EN 301 489-1 V2.2.3 EN 61000-4-11	0 % UT* for 0.5per 0 % UT* for 1per 70 % UT* for 25per 0 % UT* for 250per	Pass

Remark:

Pass	Test item meets the requirement
Fail	Test item does not meet the requirement
N/A	Test case does not apply to the test object
A.M	Amplitude Modulation
†	Differential Mode
‡	Common Mode
*	U _T is the nominal supply voltage



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3 General Information

3.1 General Description of E.U.T.

Product Name : Wireless mouse in bamboo

Model No. : MO2085

Remark : ---

3.2 Details of E.U.T.

Technical Data : Wireless mouse: Battery 1.5V (1*1.5V AA)
Dongle: DC 5V

3.3 Description of Support Units

The EUT has been tested as an independent unit. MO2085 is the test sample. The full tests were performed in the following conditions:

- 1) For dongle: the tests were performed with the notebook input (AC 230V/50Hz) specified by the laboratory.
- 2) For mouse: the tests were performed with battery 1.5V input.

3.4 Standards Applicable for Testing

The tests were performed according to following standards:

ETSI EN 301 489-1 V2.2.3 (2019-11)	ElectroMagnetic Compatibility (EMC) standard for radio equipment and services; Part 1: Common technical requirements; Harmonised Standard for ElectroMagnetic Compatibility
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ETSI EN 301 489-3 V2.3.2 (2023-01)	ElectroMagnetic Compatibility (EMC) standard for radio equipment and services; Part 3: Specific conditions for Short Range Devices (SRD) operating on frequencies between 9 kHz and 246 GHz; Harmonised Standard for ElectroMagnetic Compatibility
---------------------------------------	---

3.5 Test Facility

The test facility has a test site registered with the following organizations:

- **ISED – Registration No.: 21895**

Waltek Testing Group (Foshan) Co., Ltd. has been registered and fully described in a report filed with the Innovation, Science and Economic Development Canada (ISED). The acceptance letter from the ISED is maintained in our files. Registration ISED number: 21895.

- **FCC – Registration No.: 820106**

Waltek Testing Group (Foshan) Co., Ltd. EMC Laboratory has been registered and fully described in a report filed with the (FCC) Federal Communications Commission. The acceptance letter from the FCC is maintained in our files. Registration 820106.

- **NVLAP – Lab Code: 600191-0**

Waltek Testing Group (Foshan) Co., Ltd. EMC Laboratory is accredited by the National Voluntary Laboratory Accreditation Program (NVLAP/NIST). NVLAP Code: 600191-0.

This report must not be used by the client to claim product certification, approval, or endorsement by NVLAP, NIST, or any agency of the Federal Government.



3.6 Subcontracted

Whether parts of tests for the product have been subcontracted to other labs:

☐ Yes ☒ No

If Yes, list the related test items and lab information:

Test items: ---

Lab information:---

3.7 Abnormalities from Standard Conditions

None.

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4 Equipment Used during Test

4.1 Equipment List

☐ Mains Terminal Disturbance Voltage 1#(Conducted Emission)						
Item	Equipment	Manufacturer	Model No.	Serial No.	Cal Date	Due Date
1.	EMI Test Receiver	R&S	ESR3	102423	2025-01-06	2026-01-05
2.	LISN	R&S	ENV216	101343	2025-01-06	2026-01-05
3.	Cable	HUBER+SUHNER	CBL2-NN-6M	223NN624	2025-01-06	2026-01-05
4.	Switch	CD	RSU-A4	RSUA4008	2025-01-06	2026-01-05
☒ Mains Terminal Disturbance Voltage 2#(Conducted Emission)						
Item	Equipment	Manufacturer	Model No.	Serial No.	Cal Date	Due Date
1.	EMI Test Receiver	R&S	ESCI	101178	2025-01-06	2026-01-05
2.	LISN	R&S	ENV216	101215	2025-01-07	2026-01-06
3.	Cable 22	Times Microwave Systems	LMR195UF-BMNM-5.00M	---	2025-01-08	2026-01-07
4.	Switch	ESE	RSU/M2	---	2025-01-06	2026-01-05
☐ Mains Terminal Disturbance Voltage 3#(Conducted Emission)						
Item	Equipment	Manufacturer	Model No.	Serial No.	Cal Date	Due Date
1.	EMI Test Receiver	R&S	ESR3	102842	2025-01-06	2026-01-05
2.	LISN	R&S	ENV216	101542	2025-01-06	2026-01-05
3.	Cable 12	YIHENG	LMR195UF-NMNM-2.5	---	2025-01-06	2026-01-05
4.	Manual RF Switch	Top Precision	SW-2	RSU0402	2025-01-06	2026-01-05
☐ Radiated Emission (30MHz to 1GHz) 1#						
Item	Equipment	Manufacturer	Model No.	Serial No.	Cal Date	Due Date
1.	3m Semi-anechoic Chamber	CHANGCHUANG	9m×6m×6m	---	2024-01-05	2027-01-04
2.	EMI Test Receiver	R&S	ESR7	101566	2025-01-06	2026-01-05
3.	Trilog Broadband Antenna	SCHWARZBECK	VULB 9162	9162-117	2025-01-12	2026-01-11
4.	Cable 20	Times Microwave Systems	RG223-NMNM-10M	---	2025-01-06	2026-01-05
5.	Cable 21	Times Microwave Systems	RG223-NMNM-3M	---	2025-01-06	2026-01-05
☒ Radiated Emission (30MHz to 1GHz) 2#						
Item	Equipment	Manufacturer	Model No.	Serial No.	Cal Date	Due Date
1.	3m Semi-anechoic Chamber	YIHENG	9m×6m×6m	YH2021071801	2024-01-06	2027-01-05
2.	EMI Test Receiver	R&S	ESR7	102454	2025-01-06	2026-01-05
3.	Trilog Broadband Antenna	SCHWARZBECK	VULB 9163	01418	2025-02-08	2026-02-07
4.	Cable 14	YIHENG	LMR240UF-NMSM-7.5	---	2025-01-06	2026-01-05



☒ Radiated Emission (1GHz to 6GHz) 1#						
Item	Equipment	Manufacturer	Model No.	Serial No.	Cal Date	Due Date
1.	3m Semi-anechoic Chamber	CHANGCHUANG	9m×6m×6m	-	2024-01-05	2027-01-04
2.	EMI Test Receiver	R&S	ESR7	101566	2025-01-06	2026-01-05
3.	Broad-band Horn Antenna	SCHWARZBECK	BBHA 9120 D	01561	2025-01-13	2026-01-12
4.	Coaxial Cable (above 1GHz)	Times-Microwave	CBL5-NN	-	2025-01-06	2026-01-05
5.	Preamplifier	Lunar E M	LNA1G18-40	20160501002	2025-01-06	2026-01-05
☐ Radiated Emission (1GHz to 6GHz) 2#						
Item	Equipment	Manufacturer	Model No.	Serial No.	Cal Date	Due Date
1.	3m Semi-anechoic Chamber	YIHENG	9m×6m×6m	YH2021071801	2024-01-06	2027-01-05
2.	EMI Test Receiver	R&S	ESR7	102454	2025-01-06	2026-01-05
3.	Broad-band Horn Antenna	SCHWARZBECK	BBHA9120D	02465	2025-01-13	2026-01-12
4.	Coaxial Cable (above 1GHz)	Times-Microwave Systems	SFT205-NMSM-7	-	2025-01-06	2026-01-05
5.	Preamplifier	Tonscend	TAP0118045	AP21J806168	2025-01-06	2026-01-05
☒ ESD						
Item	Equipment	Manufacturer	Model No.	Serial No.	Cal Date	Due Date
1.	ESD Simulator	TESEQ	NSG437	521	2025-01-06	2026-01-05
☒ EFT & Voltage Dips and Interruptions						
Item	Equipment	Manufacturer	Model No.	Serial No.	Cal Date	Due Date
1.	EMS test system	TESEQ	NSG3040	1858	2025-01-06	2026-01-05
2.	Step transformer	TESEQ	INA6501	206	2025-01-06	2026-01-05
3.	Coupling clamp	TESEQ	CDN8014	31405	2025-01-07	2026-01-06
☒ Surge						
Item	Equipment	Manufacturer	Model No.	Serial No.	Cal Date	Due Date
1.	Surge Simulator	TESEQ	NSG3060	1395	2025-01-06	2026-01-05
☒ Injected Currents						
Item	Equipment	Manufacturer	Model No.	Serial No.	Cal Date	Due Date
1.	Conducted Immunity test system	TESEQ	NSG4070	45345	2025-01-06	2026-01-05
2.	CDN	TESEQ	CDN M016	31586	2025-01-07	2026-01-06
3.	EM Clamp	TESEQ	KEMZ801	32362	2025-01-06	2026-01-05
4.	6dB Attenuator	TESEQ	ATN6075	32122	2025-01-07	2026-01-06
☒ Radio-frequency electromagnetic fields						
Item	Equipment	Manufacturer	Model No.	Serial No.	Cal Date	Due Date
1.	RF Power Amplifier	MICOTOP	MPA-80-1000-250	MPA2405139	2025-01-06	2026-01-05
2.	RF Power Amplifier	MICOTOP	MPA-1000-6000-100	MPA2405140	2025-01-06	2026-01-05



3.	Stacked double logarithmic periodic antenna	SCHWARZBECK	STLP9128E-SPECIAL	142	2025-01-15	2026-01-14
4.	Stacked double logarithmic periodic antenna	SCHWARZBECK	STLP 9149	476	2025-01-13	2026-01-12
5.	Analog signal generator	RS	SMB100A	105566	2025-01-06	2026-01-05
6.	Power meter	RS	NRP6A	101133	2025-01-06	2026-01-05
7.	Power meter	RS	NRP6A	101134	2025-01-06	2026-01-05

☐: Not Used

☒: Used

4.2 Software List

Description	Manufacturer	Model	Version
EMI Test Software (Conducted Emission 1#)	FARATRONIC	EZ-EMC	EMEC-3A1
EMI Test Software (Conducted Emission 2#)	FARATRONIC	EZ-CON	FARAD-3A1.1+
EMI Test Software (Conducted Emission 3#)	FARATRONIC	EZ-EMC	EMC-CON 3A1.1+
EMI Test Software (Radiated Emission 1#)	FARATRONIC	EZ-EMC	RA-03A1-2
EMI Test Software (Radiated Emission 2#)	FARATRONIC	EZ-EMC	RA-03A1-2
Radiated Immunity Test Software	Chinese EMC	EMS	V1.0.0.0

4.3 Measurement Uncertainty

Test Item	Frequency Range	Uncertainty	Note
Conducted Emission	150kHz~30MHz	±2.6dB	(1)
Radiated Emission	30MHz~1GHz	±4.5dB	(1)
Radiated Emission	1GHz~6GHz	±4.5dB	(1)

(1) This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of $k=2$.



4.4 Special Accessories and Auxiliary Equipment

Item	Equipment	Manufacturer	Model No.
1.	Notebook	Lenovo	ThinkPad Edge E430

4.5 Decision Rule

Compliance or non-compliance with a disturbance limit shall be determined in the following manner.

If U_{LAB} is less than or equal to U_{cispr} , then

- Compliance is deemed to occur if no measured disturbance level exceeds the disturbance limit;
- Non-compliance is deemed to occur if any measured disturbance level exceeds the disturbance limit.

If U_{LAB} is greater than U_{cispr} , then

- Compliance is deemed to occur if no measured disturbance level, increased by $(U_{LAB} - U_{cispr})$, exceeds the disturbance limit;
- Non-compliance is deemed to occur if any measured disturbance level, increased by $(U_{LAB} - U_{cispr})$, exceeds the disturbance limit.

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5 EMC Requirements for Emissions

5.1 Conducted Emission

Test Requirement	ETSI EN 301 489-3
Test Method	ETSI EN 301 489-1, EN 55032 Class B
Frequency Range	150kHz to 30MHz
Class/Severity	Class B/ Table A.10 of EN 55032
Ports	AC Mains
Detector	Peak for pre-scan (9kHz Resolution Bandwidth)

5.1.1 E.U.T. Operation

Operating Environment:

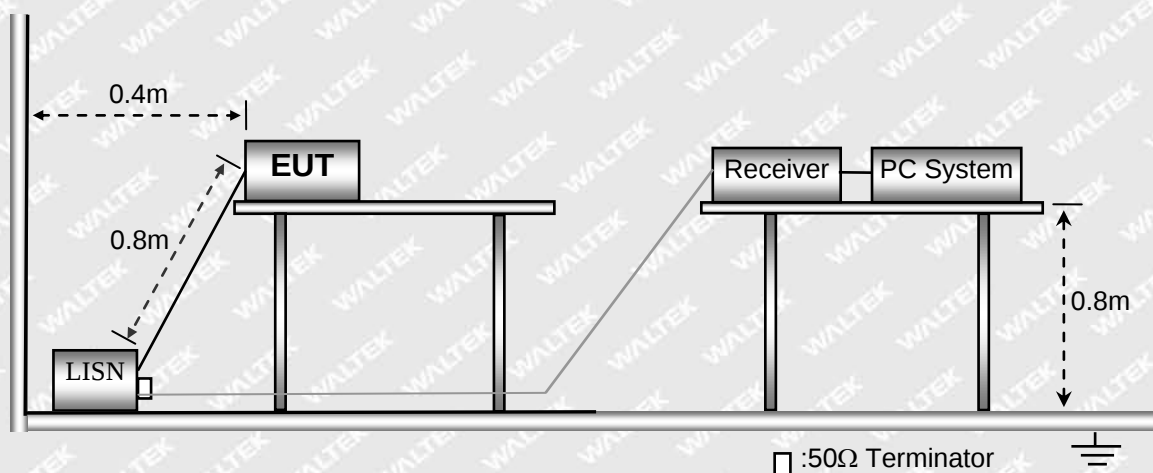
Temperature	20.8°C
Humidity	49.3%RH
Atmospheric Pressure	101.2kPa

EUT Operation:

Input Voltage	Dongle: DC 5V (Notebook with AC 230V/50Hz input) Mouse: Battery 1.5V
Operating Mode	Communication mode

5.1.2 Test Setup

The conducted emission tests were performed using the setup accordance with the EN 55032.





5.1.3 Corrected Amplitude & Margin Calculation

The Corrected factor is calculated by adding LISN VDF(Voltage Division Factor), Cable Loss and Transient Limiter Attenuation. The basic equation is as follows:

$$\text{Measurement} = \text{Reading Level} + \text{Correct Factor}$$

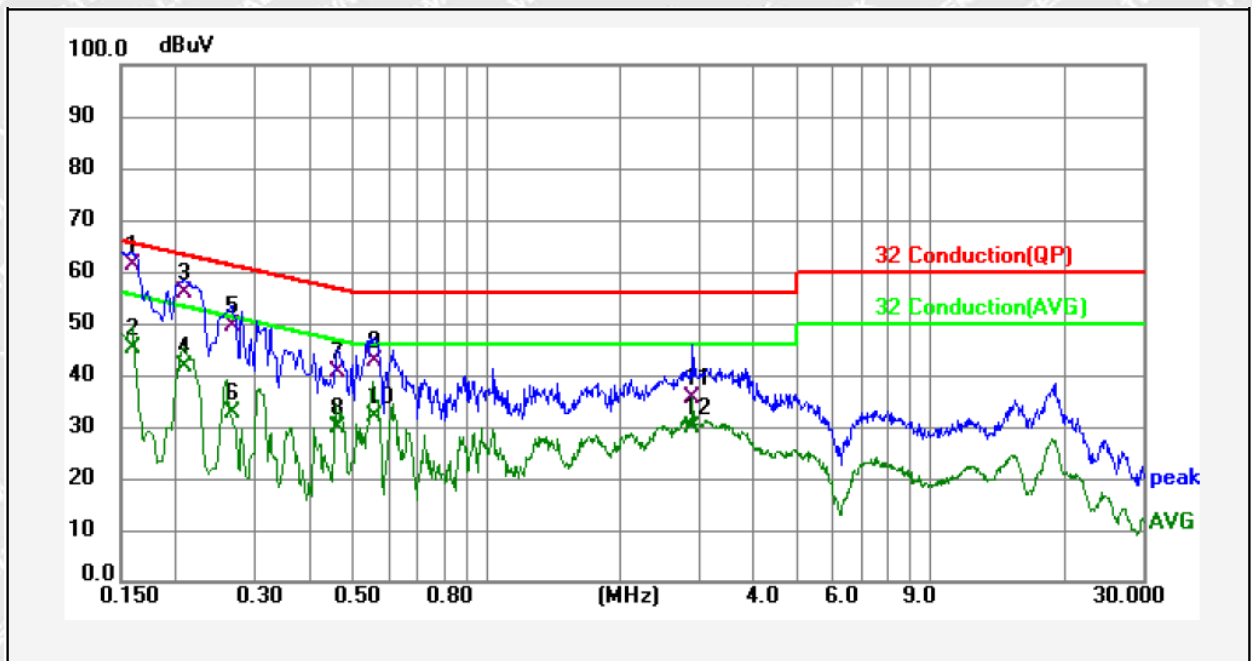
$$\text{Correct Factor} = \text{LISN VDF} + \text{Cable Loss}$$

The "Margin" column of the following data tables indicates the degree of compliance with the applicable limit. For example, a margin of -7dB means the emission is 7dB below the limit. The equation for margin calculation is as follows:

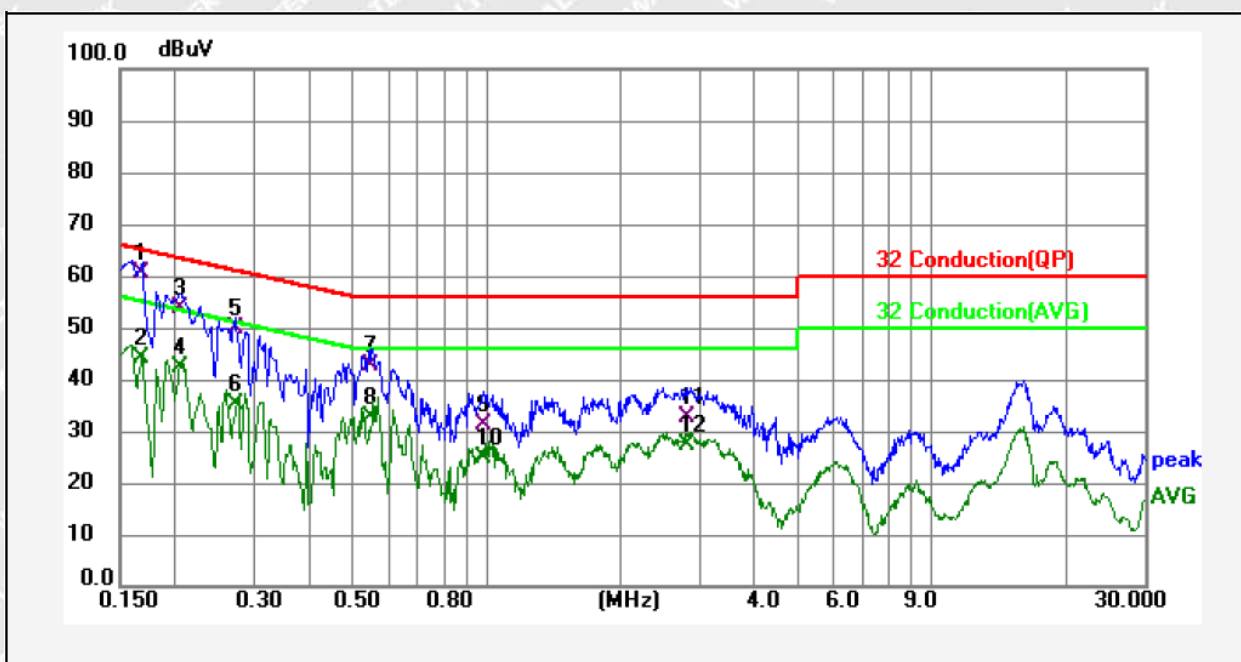
$$\text{Margin} = \text{Measurement} - \text{Limit}$$

5.1.4 Test Result

Live Line



No.	Freq. (MHz)	Reading (dBuV)	Factor (dB)	Result (dBuV)	Limit (dBuV)	Margin (dB)	Detector	Remark
1	0.159	51.74	9.61	61.35	65.52	-4.17	QP	
2	0.159	35.46	9.61	45.07	55.52	-10.45	AVG	
3	0.208	46.42	9.61	56.03	63.28	-7.25	QP	
4	0.208	32.01	9.61	41.62	53.28	-11.66	AVG	
5	0.267	40.03	9.61	49.64	61.21	-11.57	QP	
6	0.267	22.98	9.61	32.59	51.21	-18.62	AVG	
7	0.461	30.99	9.63	40.62	56.67	-16.05	QP	
8	0.461	20.18	9.63	29.81	46.67	-16.86	AVG	
9	0.559	33.08	9.65	42.73	56.00	-13.27	QP	
10	0.559	22.44	9.65	32.09	46.00	-13.91	AVG	
11	2.909	25.76	9.79	35.55	56.00	-20.45	QP	
12	2.909	19.86	9.79	29.65	46.00	-16.35	AVG	

**Neutral Line**

No.	Freq. (MHz)	Reading (dBuV)	Factor (dB)	Result (dBuV)	Limit (dBuV)	Margin (dB)	Detector	Remark
1	0.168	50.98	9.53	60.51	65.06	-4.55	QP	
2	0.168	34.70	9.53	44.23	55.06	-10.83	AVG	
3	0.204	44.28	9.53	53.81	63.45	-9.64	QP	
4	0.204	32.77	9.53	42.30	53.45	-11.15	AVG	
5	0.272	40.36	9.54	49.90	61.06	-11.16	QP	
6	0.272	25.66	9.54	35.20	51.06	-15.86	AVG	
7	0.550	33.08	9.58	42.66	56.00	-13.34	QP	
8	0.550	23.12	9.58	32.70	46.00	-13.30	AVG	
9	0.983	21.76	9.60	31.36	56.00	-24.64	QP	
10	0.983	15.36	9.60	24.96	46.00	-21.04	AVG	
11	2.823	23.07	9.70	32.77	56.00	-23.23	QP	
12	2.823	17.69	9.70	27.39	46.00	-18.61	AVG	



5.2 Radiated Emission

Test Requirement	ETSI EN 301 489-3
Test Method	ETSI EN 301 489-1, EN 55032, Class B
Frequency Range	30MHz to 1GHz, 1GHz to 6GHz
Class/Severity	Class B/ Table A.4 and A.5 of EN 55032
Detector	Peak for pre-scan (120kHz Resolution Bandwidth Below 1GHz; 1MHz Resolution Bandwidth Above 1GHz)

5.2.1 EUT Operation:

Operating Environment:

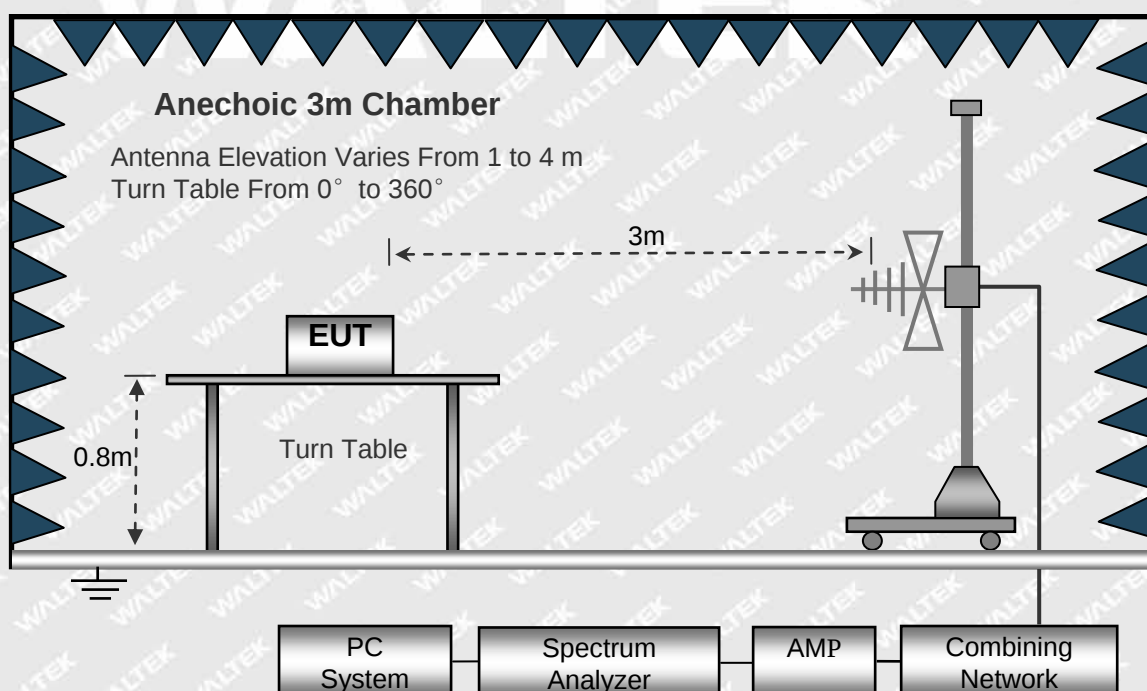
Temperature	22.6°C
Humidity	50.9%RH
Atmospheric Pressure	101.2kPa

EUT Operation:

Input Voltage	Dongle: DC 5V (Notebook with AC 230V/50Hz input) Mouse: Battery 1.5V
Operating Mode	Communication mode

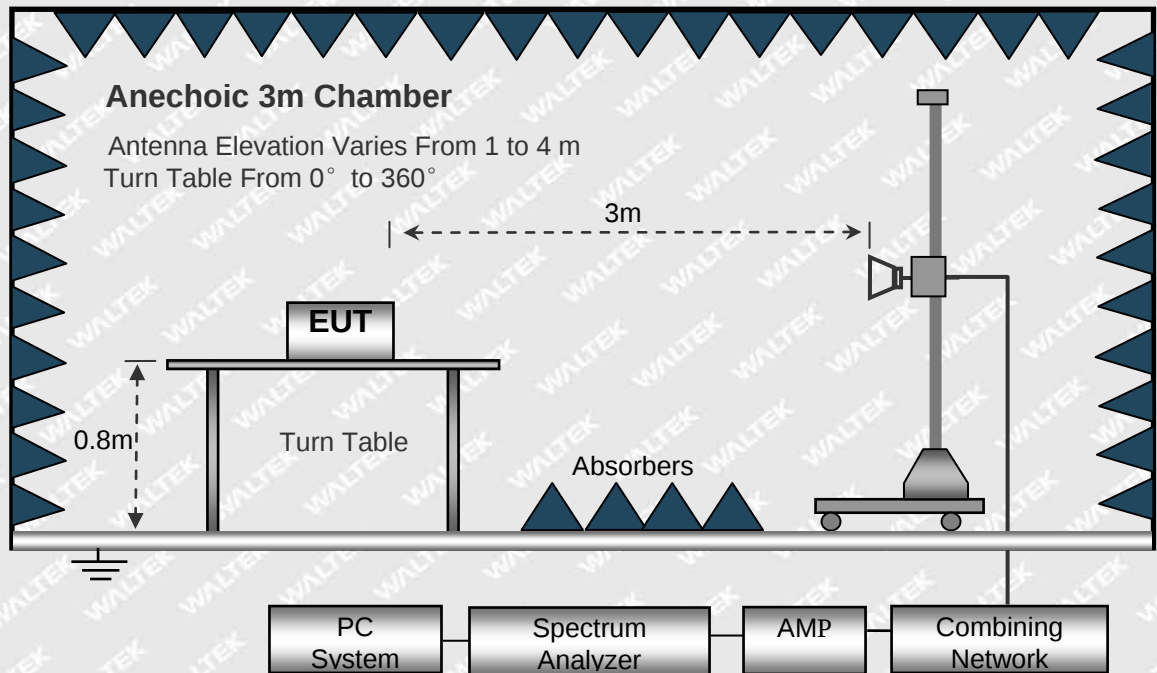
5.2.2 Test Setup

The radiated emission tests were performed using the setup accordance with the EN 55032.
Frequency Range: Below 1 GHz





Frequency Range: Above 1 GHz



5.2.3 Corrected Amplitude & Margin Calculation

The Corrected Amplitude is calculated by adding the Antenna Factor and Cable Factor, and subtracting the Amplifier Gain from the Amplitude reading. The basic equation is as follows:

$$\text{Corr. Ampl.} = \text{Indicated Reading} + \text{Corr. Factor}$$

$$\text{Corr. Factor} = \text{Antenna Factor} + \text{Cable Factor} - \text{Amplifier Gain}$$

The "Margin" column of the following data tables indicates the degree of compliance with the applicable limit. For example, a margin of -7dB means the emission is 7dB below the maximum limit.

The equation for margin calculation is as follows:

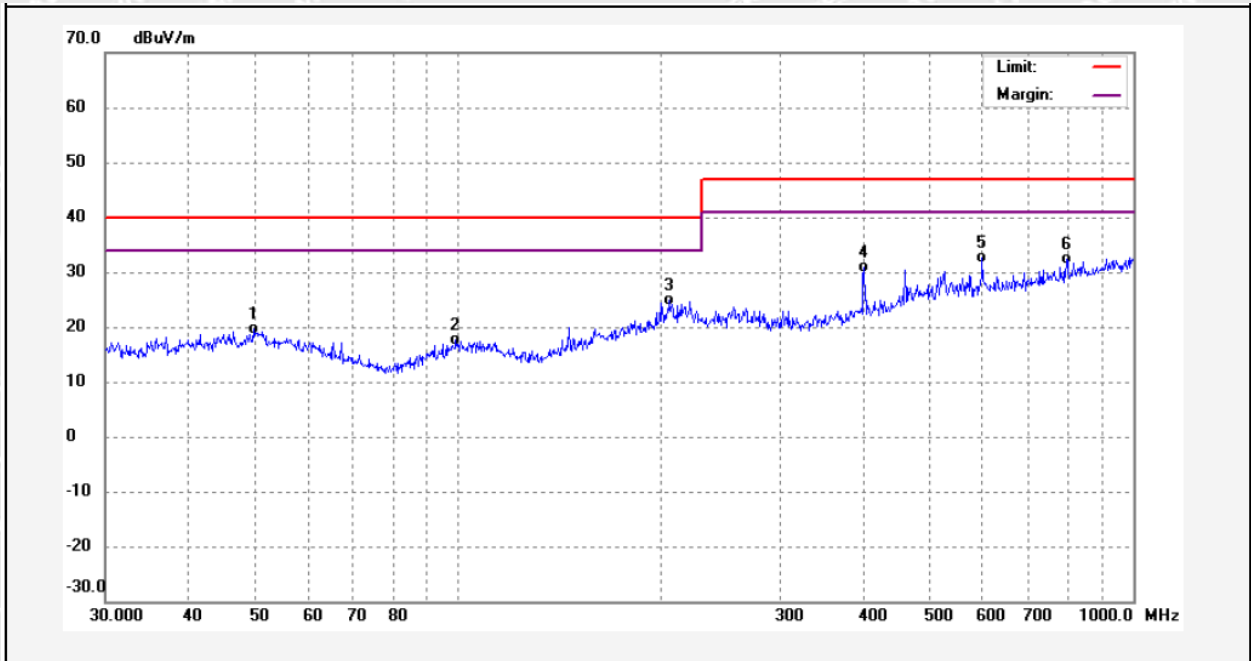
$$\text{Margin} = \text{Corr. Ampl.} - \text{Limit}$$



5.2.4 Test Result

Frequency Range: 30MHz ~ 1000MHz

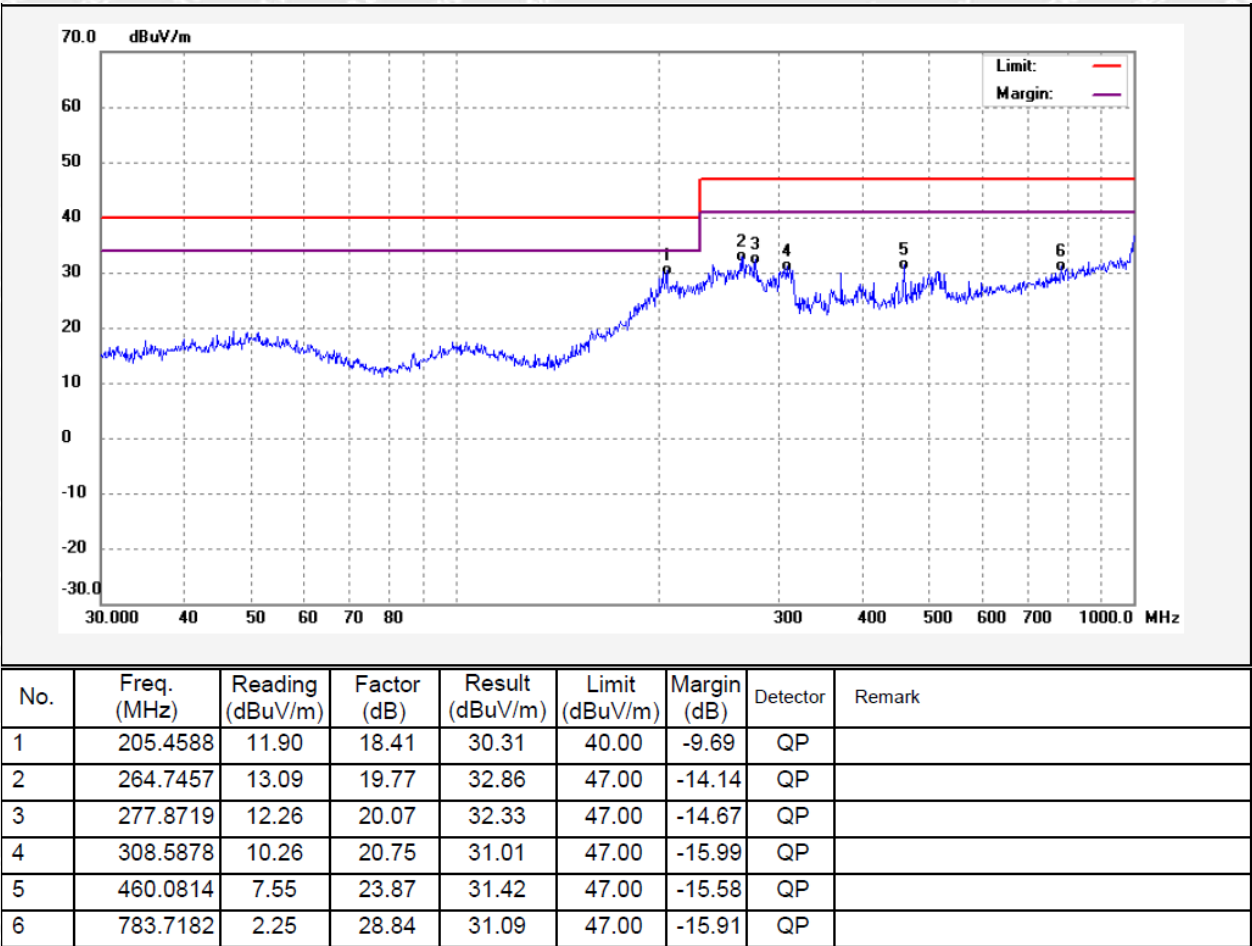
Antenna Polarization: Vertical



No.	Freq. (MHz)	Reading (dBuV/m)	Factor (dB)	Result (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	Remark
1	49.7940	-0.37	19.94	19.57	40.00	-20.43	QP	
2	99.2493	-0.75	18.26	17.51	40.00	-22.49	QP	
3	206.0360	6.49	18.38	24.87	40.00	-15.13	QP	
4	399.5903	8.13	22.75	30.88	47.00	-16.12	QP	
5	597.6424	6.17	26.51	32.68	47.00	-14.32	QP	
6	796.7415	3.52	28.96	32.48	47.00	-14.52	QP	

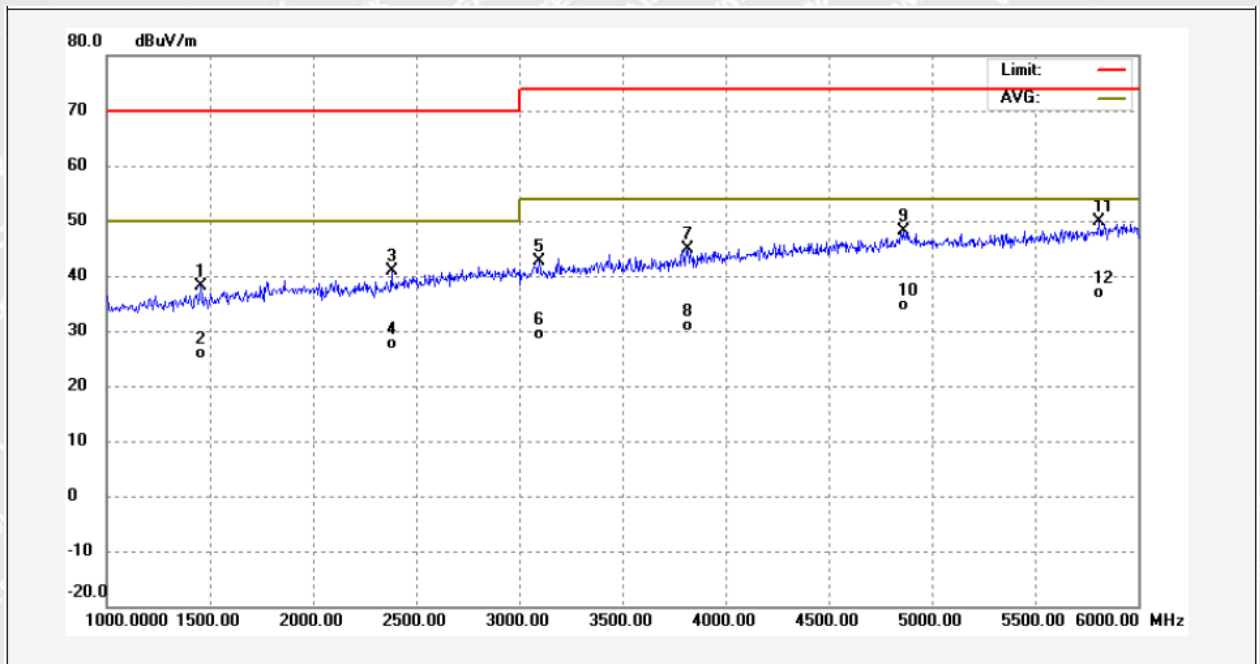


Antenna Polarization: Horizontal



**Frequency Range: 1000MHz ~ 6000MHz**

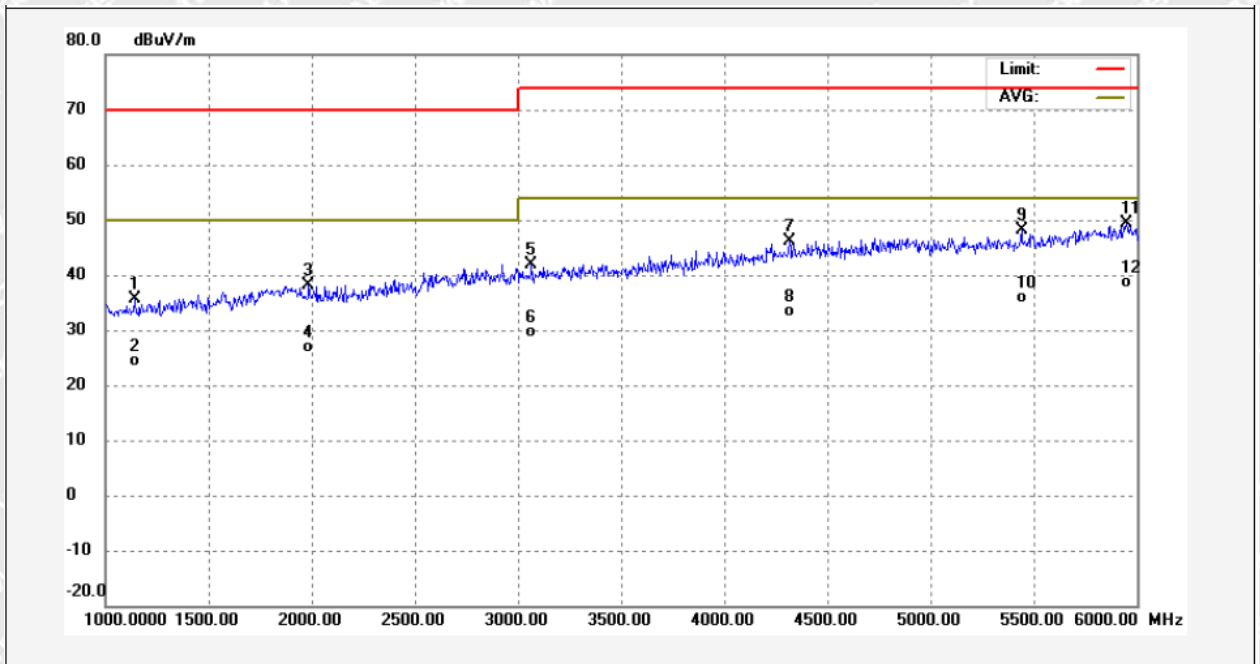
Antenna Polarization: Vertical



No.	Freq. (MHz)	Reading (dBuV/m)	Factor (dB)	Result (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	Remark
1	1456.500	9.73	28.31	38.04	70.00	-31.96	peak	
2	1456.500	-2.43	28.31	25.88	50.00	-24.12	AVG	
3	2383.000	10.94	29.82	40.76	70.00	-29.24	peak	
4	2383.000	-2.18	29.82	27.64	50.00	-22.36	AVG	
5	3095.000	10.74	31.84	42.58	74.00	-31.42	peak	
6	3095.000	-2.53	31.84	29.31	54.00	-24.69	AVG	
7	3817.500	11.37	33.48	44.85	74.00	-29.15	peak	
8	3817.500	-2.58	33.48	30.90	54.00	-23.10	AVG	
9	4860.000	12.46	35.65	48.11	74.00	-25.89	peak	
10	4860.000	-0.99	35.65	34.66	54.00	-19.34	AVG	
11	5810.500	12.83	37.07	49.90	74.00	-24.10	peak	
12	5810.500	-0.23	37.07	36.84	54.00	-17.16	AVG	



Antenna Polarization: Horizontal



No.	Freq. (MHz)	Reading (dBuV/m)	Factor (dB)	Result (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	Remark
1	1144.500	8.14	27.56	35.70	70.00	-34.30	peak	
2	1144.500	-3.26	27.56	24.30	50.00	-25.70	AVG	
3	1986.000	8.83	29.19	38.02	70.00	-31.98	peak	
4	1986.000	-2.42	29.19	26.77	50.00	-23.23	AVG	
5	3069.000	10.19	31.81	42.00	74.00	-32.00	peak	
6	3069.000	-2.12	31.81	29.69	54.00	-24.31	AVG	
7	4315.000	11.54	34.53	46.07	74.00	-27.93	peak	
8	4315.000	-1.25	34.53	33.28	54.00	-20.72	AVG	
9	5444.500	11.65	36.45	48.10	74.00	-25.90	peak	
10	5444.500	-0.65	36.45	35.80	54.00	-18.20	AVG	
11	5950.500	12.04	37.34	49.38	74.00	-24.62	peak	
12	5950.500	1.32	37.34	38.66	54.00	-15.34	AVG	



6 EMC Requirement for Immunity

6.1 Performance Criteria

6.1.1 General performance criteria

The performance criteria are used to take a decision on whether a radio equipment passes or fails immunity tests.

For the purpose of the present document two categories of performance criteria apply:

- Performance criteria for continuous phenomena.
- Performance criteria for transient phenomena.

6.1.2 Performance criteria for continuous phenomena

During the test, the equipment shall:

- continue to operate as intended;
- not unintentionally transmit;
- not unintentionally change its operating state;
- not unintentionally change critical stored data.

6.1.3 Performance criteria for transient phenomena

For all ports and transient phenomena with the exception described below, the following applies:

- The application of the transient phenomena shall not result in a change of the mode of operation (e.g. unintended transmission) or the loss of critical stored data.
- After application of the transient phenomena, the equipment shall operate as intended.

For surges applied to symmetrically operated wired network ports intended to be connected directly to outdoor lines the following criteria applies:

- For products with only one symmetrical port intended for connection to outdoor lines, loss of function is allowed, provided the function is self-recoverable, or can be otherwise restored. Information stored in non-volatile memory, or protected by a battery backup, shall not be lost.
- For products with more than one symmetrical port intended for connection to outdoor lines, loss of function on the port under test is allowed, provided the function is self-recoverable. Information stored in non-volatile memory, or protected by a battery backup, shall not be lost.



6.2 Electrostatic Discharge(ESD)

Test Requirement	: ETSI EN 301 489-3
Test Method	: ETSI EN 301 489-1, EN 61000-4-2
Discharge Impedance	: 330 Ω / 150 pF
Discharge Voltage	: Air Discharge: +/-2,4,8 KV Contact Discharge: +/-2,4 KV HCP & VCP: +/-2,4 KV
Polarity	: Positive & Negative
Discharge Repeat Times	: At Least 20 times at each test point
Discharge Mode	: Single Discharge
Discharge Period	: 1 second minimum

6.2.1 E.U.T. Operation

Operating Environment:

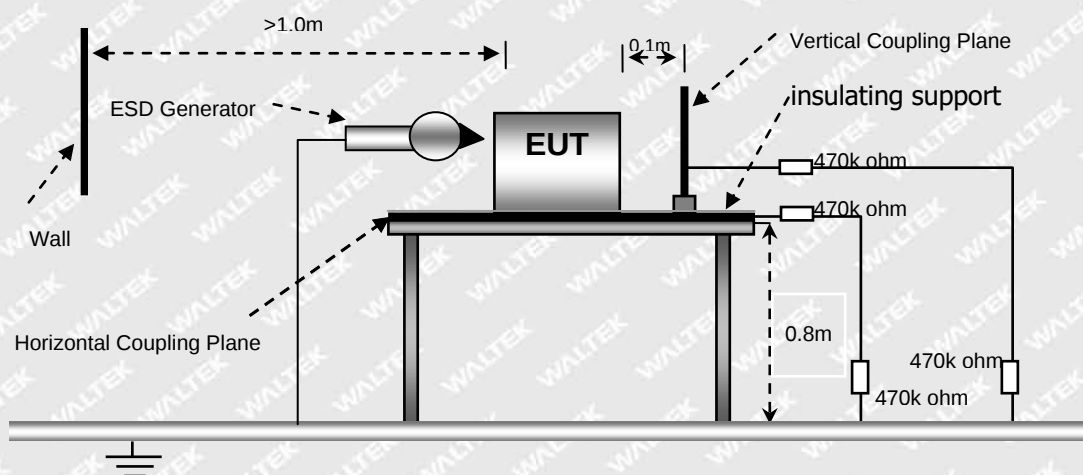
Temperature	: 22.6°C
Humidity	: 52.9%RH
Atmospheric Pressure	: 101.5kPa

EUT Operation:

Input Voltage	: Dongle: DC 5V (Notebook with AC 230V/50Hz input) Mouse: Battery 1.5V
Operating Mode	: Communication mode

6.2.2 Block Diagram of Setup

The ESD test was performed in accordance with the EN 61000-4-2.





6.2.3 Test Result

Direct Discharge			Performance Criteria	
Discharge Level (kV)	Performance Criterion	Test Point	Contact Discharge	Air Discharge
$\pm 2 / \pm 4 / \pm 8$	TT	1	N/A	Pass*
$\pm 2 / \pm 4$	TT	2	Pass*	N/A

Remark:

Test points 1. All Exposed Surface & Seams; 2. All metallic part

* During the test no deviation was detected to the selected operation mode(s)

Indirect Discharge			Performance Criteria	
Discharge Level (kV)	Performance Criterion	Test Point	Horizontal Coupling	Vertical Coupling
$\pm 2 / \pm 4$	TT	1	Pass*	Pass*

Remark:

Test points 1. All sides

* During the test no deviation was detected to the selected operation mode(s)

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6.3 RF Electromagnetic Field (80MHz to 6 000MHz) (RS)

Test Requirement	ETSI EN 301 489-3
Test Method	ETSI EN 301 489-1, EN 61000-4-3
Face of EUT	Front, Back, Left, Right
Frequency Range	80MHz to 6 000MHz
Test Level	3V/m
Modulation	80%, 1kHz Amplitude Modulation.
Antenna polarisation	Horizontal& Vertical

6.3.1 E.U.T. Operation

Operating Environment:

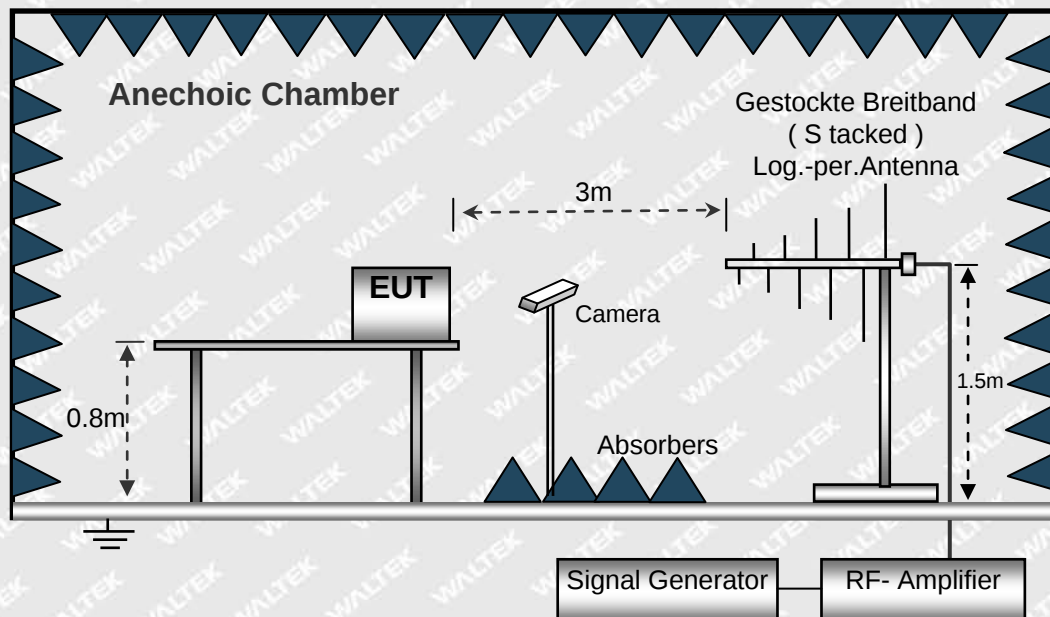
Temperature	23.1°C
Humidity	52.4%RH
Atmospheric Pressure	101.7kPa

EUT Operation:

Input Voltage	Dongle: DC 5V (Notebook with AC 230V/50Hz input) Mouse: Battery 1.5V
Operating Mode	Communication mode

6.3.2 Block Diagram of Setup

The Radiated Immunity test was performed in accordance with the EN 61000-4-3.





6.3.3 Test Result

Frequency	Face of EUT	Antenna polarisation	Test Level	Step Size	Dwell Time	Performance Criterion	Result
80MHz to 1000MHz	Front, Back, Left, Right	Horizontal	3V/m	1%	1s	CT	Pass*
80MHz to 1000MHz	Front, Back, Left, Right	Vertical	3V/m	1%	1s	CT	Pass*
1000MHz to 6000MHz	Front, Back, Left, Right	Horizontal	3V/m	1%	1s	CT	Pass*
1000MHz to 6000MHz	Front, Back, Left, Right	Vertical	3V/m	1%	1s	CT	Pass*

Remark:

* During the test no deviation was detected to the selected operation mode(s)

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6.4 Fast Transients Common Mode (EFT)

Test Requirement	: ETSI EN 301 489-3
Test Method	: ETSI EN 301 489-1, EN 61000-4-4
Polarity	: Positive & Negative
Repetition Frequency.....	: 5kHz
Burst Duration	: 300ms
Test Duration	: 2 minutes per level & polarity

6.4.1 E.U.T. Operation

Operating Environment:

Temperature.....	: 22.6°C
Humidity	: 52.8%RH
Atmospheric Pressure	: 101.5kPa

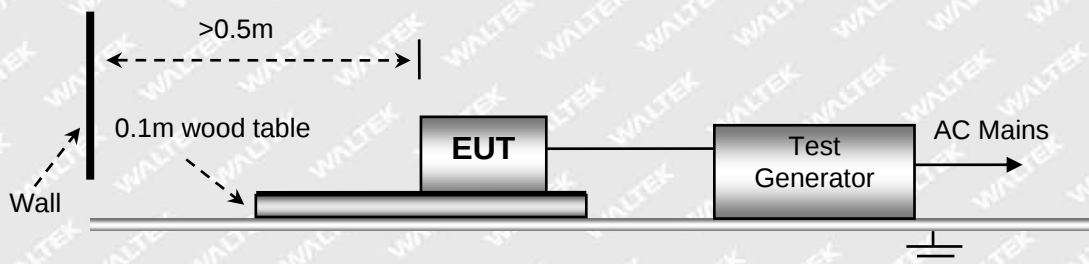
EUT Operation:

Input Voltage.....	: Dongle: DC 5V (Notebook with AC 230V/50Hz input) Mouse: Battery 1.5V
Operating Mode	: Communication mode

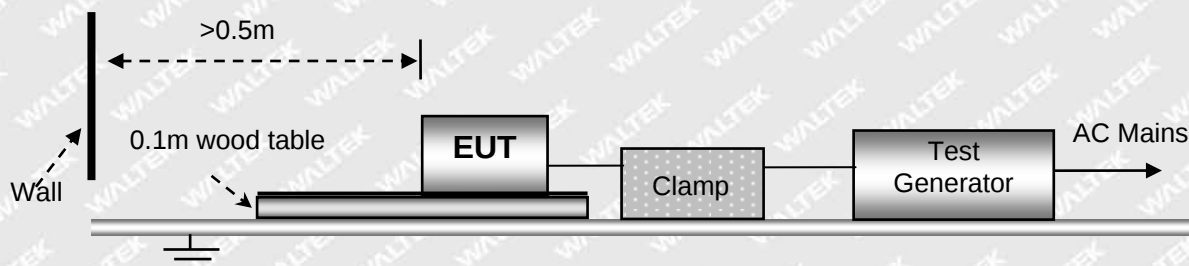
6.4.2 Block Diagram of Test Setup

The Electrical Fast Transients Immunity test was performed in accordance with the EN 61000-4-4.

For AC Mains or DC Ports:



For Signal, Wired network or Control Ports:





6.4.3 Test Result

Test Port	Test Level(kV)	Performance Criterion	Result
AC mains power port	±1.0	TT	Pass*
DC power port	±0.5	TT	N/A
Signal port	±0.5	TT	N/A
Control port	±0.5	TT	N/A
Wired network port	±0.5	TT	N/A

Remark:

* During the test no deviation was detected to the selected operation mode(s)

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6.5 Surges

Test Requirement	: ETSI EN 301 489-3
Test Method	: ETSI EN 301 489-1, EN 61000-4-5
Interval	: 60s between each surge
No. of surges	: 5 positive, 5 negative at 0°, 90°, 180°, 270°.

6.5.1 E.U.T. Operation

Operating Environment:

Temperature	: 23.0°C
Humidity	: 52.8%RH
Atmospheric Pressure	: 101.6kPa

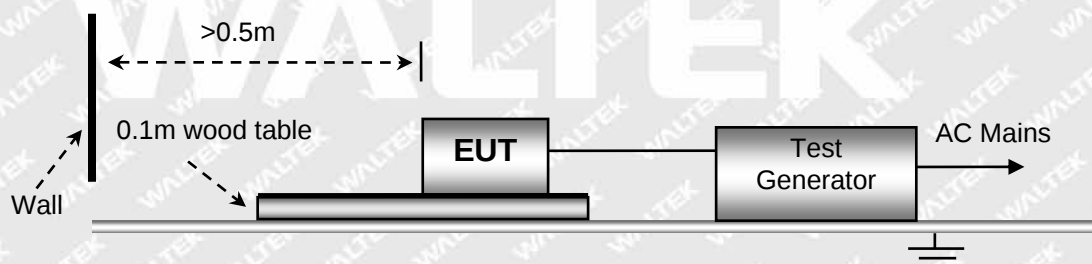
EUT Operation:

Input Voltage	: Dongle: DC 5V (Notebook with AC 230V/50Hz input) Mouse: Battery 1.5V
Operating Mode	: Communication mode

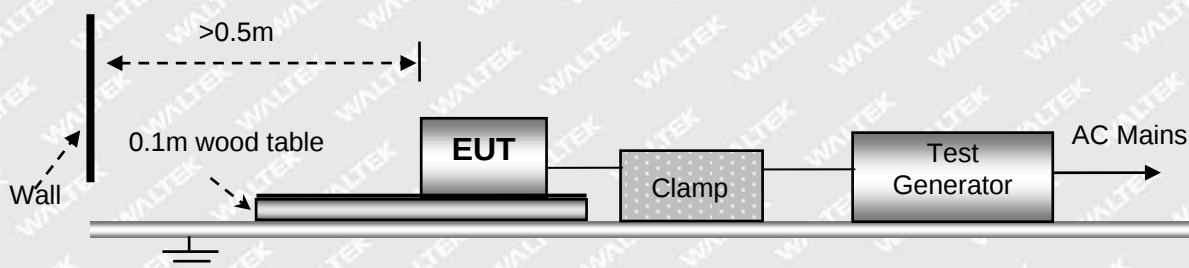
6.5.2 Block Diagram of Test Setup

The Surges Immunity test was performed in accordance with the EN 61000-4-5.

For AC Mains or DC Ports:



For Wired network port:





6.5.3 Test Result

Coupling point	Test Port	Applied Voltage (kV)	Performance criterion	Result
AC power port	Between Phase And Phase	±1	TT	N/A
	Between Live And Neutral	±1	TT	Pass*
	Between Live And Earth	±2	TT	N/A
	Between Neutral And Earth	±2	TT	N/A

Remark:

* During the test no deviation was detected to the selected operation mode(s)

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6.6 RF Common Mode 0,15 MHz to 80MHz (CS)

Test Requirement	: ETSI EN 301 489-3
Test Method	: ETSI EN 301 489-1, EN 61000-4-6
Frequency Range	: 150kHz to 80MHz
Test level	: 3V rms (unmodulated emf into 150 Ω)
Modulation	: 80%, 1kHz Amplitude Modulation.

6.6.1 E.U.T. Operation

Operating Environment:

Temperature	: 22.6°C
Humidity	: 53.0%RH
Atmospheric Pressure	: 101.5kPa

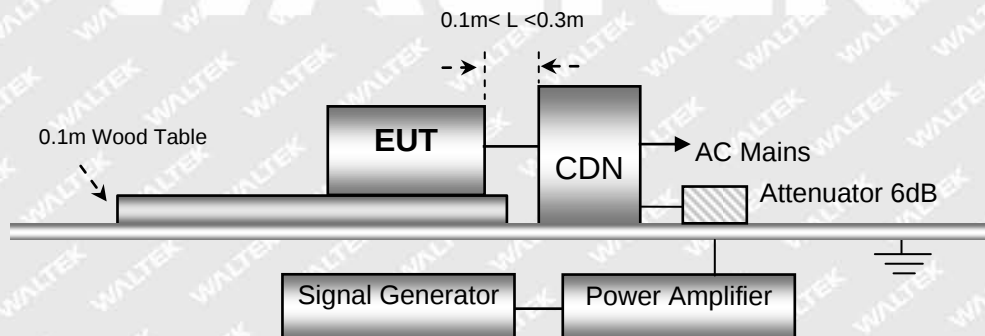
EUT Operation:

Input Voltage	: Dongle: DC 5V (Notebook with AC 230V/50Hz input) Mouse: Battery 1.5V
Operating Mode	: Communication mode

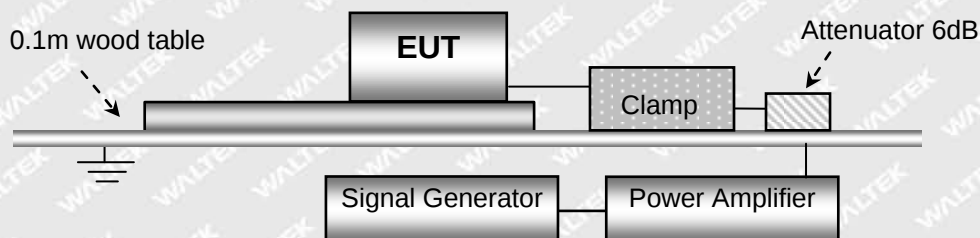
6.6.2 Block Diagram of Test Setup

The Injected Currents Immunity test was performed in accordance with the EN 61000-4-6.

For AC Mains or DC Ports:



For Signal, Wired network or Control Ports:





6.6.3 Test Result

Line	Voltage Level	Modulation	Step Size	Dwell Time	Performance Criteria	Test Result
AC mains power port	3Vr.m.s	80%, 1kHz Amp. Mod.	1%	1s	CT	Pass*
DC power port	3Vr.m.s	80%, 1kHz Amp. Mod.	1%	1s	CT	N/A
Signal port	3Vr.m.s	80%, 1kHz Amp. Mod.	1%	1s	CT	N/A
Wired network port	3Vr.m.s	80%, 1kHz Amp. Mod.	1%	1s	CT	N/A
Control port	3Vr.m.s	80%, 1kHz Amp. Mod.	1%	1s	CT	N/A

Remark:

* During the test no deviation was detected to the selected operation mode(s)

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6.7 Voltage Dips and Interruptions

Test Requirement : ETSI EN 301 489-3
Test Method : ETSI EN 301 489-1, EN 61000-4-11
No. of Dips / Interruptions : 3 per Level at 10ms intervals
Test Level(Voltage reduction) : 0%&70 % of U_T (Supply Voltage)

6.7.1 E.U.T. Operation

Operating Environment:

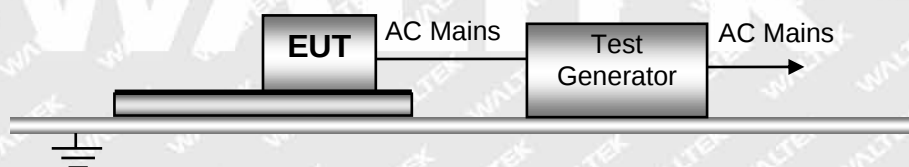
Temperature..... : 22.5°C
Humidity : 52.7%RH
Atmospheric Pressure : 101.6kPa

EUT Operation:

Input Voltage..... : Dongle: DC 5V (Notebook with AC 230V/50Hz input)
 Mouse: Battery 1.5V
Operating Mode : Communication mode

6.7.2 Block Diagram of Setup

The Voltage Dips and Interruptions Immunity test was performed in accordance with the EN 61000-4-11.



6.7.3 Test Result

Type	Test Level in % U_T	Phase	Duration	Performance criterion	Result
Voltage Dips	0	0° & 180°	0.5	TT	Pass*
	0	0° & 180°	1	TT	Pass*
	70	0° & 180°	25	TT	Pass*
Voltage Interruption	0	0° & 180°	250	TT	Pass*

Remark:

* During the test no deviation was detected to the selected operation mode(s)



7 Photographs - Test Setup

7.1 Photograph - Radiated Emissions Test Setup

Below 1000MHz



Above 1000MHz

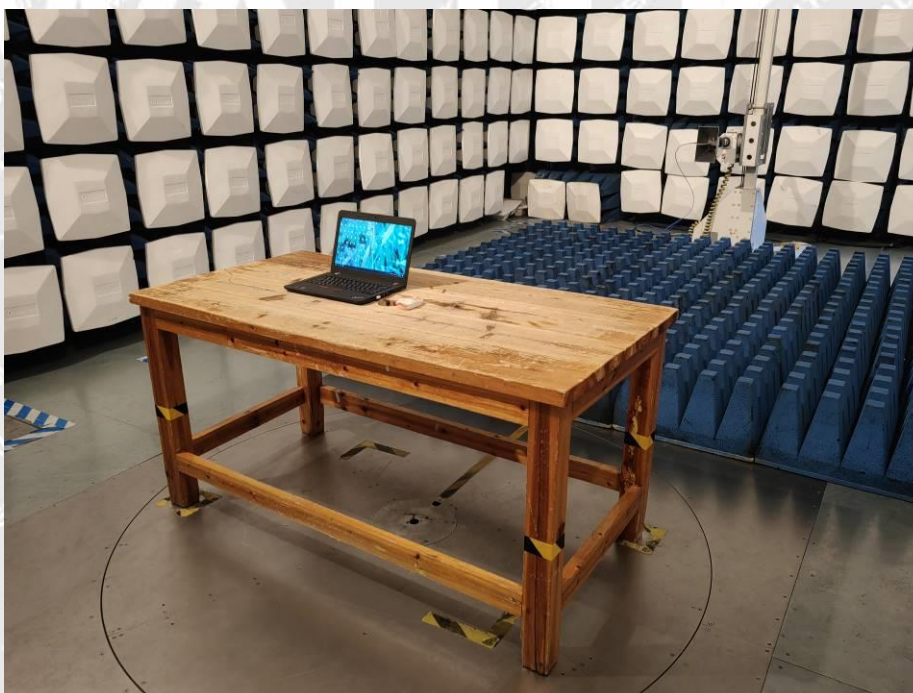




7.2 Photograph - Conducted Emissions Test Setup



7.3 Photograph - RF Electromagnetic Field Test Setup





7.4 Photograph - ESD Test Setup



7.5 Photograph - EFT Immunity Test Setup





7.6 Photograph - Surge Immunity Test Setup



7.7 Photograph - Radio-frequency Common Mode Test Setup





7.8 Photograph - Voltage Dips and Interruptions Immunity Test Setup



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8 Photographs – EUT Constructional Details

Please refer to “ANNEX” (Reference No. WTF25F11291489W).

=====End of Report=====

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中国认可
国际互认
检测
TESTING
CNAS L6478



TEST REPORT

Reference No...... : WTF25F11291490W
Applicant..... : Mid Ocean Brands B.V.
Address..... : Unit 711-716, 7/F., Tower A, 83 King Lam Street, Cheung Sha Wan,
Kowloon, Hong Kong.
Manufacturer : 106613
Address..... : ---
Product Name..... : Wireless mouse in bamboo
Model No...... : MO2085
Test specification..... : EN 55032:2015+A11:2020+A1:2020
EN 55035:2017+A11:2020
Date of Receipt sample : 2025-11-18
Date of Test : 2025-11-19
Date of Issue..... : 2025-11-29
Test Report Form No. : WEI-55032A-04B
Test Result..... : Pass

Remarks:

The results shown in this test report refer only to the sample(s) tested, this test report cannot be reproduced, except in full, without prior written permission of the company. The report would be invalid without specific stamp of test institute and the signatures of approver.

Prepared By:

Waltek Testing Group (Foshan) Co., Ltd.

Address: 1/F., Building 19, Sunlink Machinery City, Xingye 4 Road,
Guanglong Industrial Park, Chihua Neighborhood Committee, Chencun,
Shunde District, Foshan, Guangdong, China

Tel:+86-757-23811398

Fax:+86-757-23811381

E-mail:info@waltek.com.cn

Tested by:

Roy Hong

Approved by:

Danny Zhou



1 Test Summary

EMISSION				
Test Item	Test Standard		Class / Severity	Result
Mains Terminal Disturbance Voltage, 150kHz to 30MHz	EN 55032:2015+A11:2020+A1:2020		Table A.10	Pass
Radiated Emission, 30MHz to 1000MHz	EN 55032:2015+A11:2020+A1:2020		Table A.4	Pass
Radiation Emission, 1GHz to 6GHz	EN 55032:2015+A11:2020+A1:2020		Table A.5	Pass
IMMUNITY (EN 55035:2017+A11:2020)				
Test Item	Test Method	Class / Severity	Performance Criteria	Result
Electrostatic Discharge(ESD)	IEC 61000-4-2:2008	±4 Kv Contact ±8 Kv Air	B	Pass
Continuous RF Electromagnetic Field Disturbances	IEC 61000-4-3: 2006+A1+A2	3V/m, 80%, 1kHz, Amp. Mod.	A	Pass
Electrical Fast Transients (EFT)	IEC 61000-4-4:2012	AC ±1.0Kv DC ±0.5Kv	B	Pass
Surge	IEC 61000-4-5:2005	±1Kv D.M.† ±2Kv C.M.‡	B	Pass
Continuous Induced RF Disturbances, 0.15MHz to 10MHz	IEC 61000-4-6:2008	3Vr.m.s.(emf), 80%, 1kHz Amp. Mod.	A	Pass
Continuous Induced RF Disturbances, 10MHz to 30MHz		3 to 1Vr.m.s.(emf), 80%, 1kHz Amp. Mod	A	
Continuous Induced RF Disturbances, 30MHz to 80MHz		1Vr.m.s.(emf), 80%, 1kHz Amp. Mod	A	
Power-Frequency Magnetic Field	IEC 61000-4-8:2009	1A/m	A	N/A
Voltage Dips	IEC 61000-4-11:2004	< 5 % U _T * for 0.5per	B	Pass
		70 % U _T * for 25/30per	C	
Voltage Interruptions		< 5 % U _T * for 250/300per	C	

Remark:

- Pass Test item meets the requirement
- Fail Test item does not meet the requirement
- N/A Test case does not apply to the test object
- A.M Amplitude Modulation
- † Differential Mode
- ‡ Common Mode
- * U_T is the nominal supply voltage



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3 General Information

3.1 General Description of E.U.T.

Product Name : Wireless mouse in bamboo
Model No. : MO2085
Remark : ---

3.2 Details of E.U.T.

Technical Data : Wireless mouse: Battery 1.5V (1*1.5V AA)
Dongle: DC 5V

3.3 Description of Support Units

The EUT has been tested as an independent unit. MO2085 is the test sample. The full tests were performed in the following conditions:

- 1) For dongle: the tests were performed with the notebook input (AC 230V/50Hz) specified by the laboratory.
- 2) For mouse: the tests were performed with battery 1.5V input.

3.4 Standards Applicable for Testing

The tests were performed according to following standards:

EN 55032:2015+A11:2020 +A1:2020	Electromagnetic compatibility of multimedia equipment - Emission Requirements
EN 55035:2017+A11:2020	Electromagnetic compatibility of multimedia equipment - Immunity requirements

3.5 Test Facility

The test facility has a test site registered with the following organizations:

- **ISED – Registration No.: 21895**

Waltek Testing Group (Foshan) Co., Ltd. has been registered and fully described in a report filed with the Innovation, Science and Economic Development Canada (ISED). The acceptance letter from the ISED is maintained in our files. Registration ISED number: 21895.

- **FCC – Registration No.: 820106**

Waltek Testing Group (Foshan) Co., Ltd. EMC Laboratory has been registered and fully described in a report filed with the (FCC) Federal Communications Commission. The acceptance letter from the FCC is maintained in our files. Registration 820106.

- **NVLAP – Lab Code: 600191-0**

Waltek Testing Group (Foshan) Co., Ltd. EMC Laboratory is accredited by the National Voluntary Laboratory Accreditation Program (NVLAP/NIST). NVLAP Code: 600191-0.

This report must not be used by the client to claim product certification, approval, or endorsement by NVLAP, NIST, or any agency of the Federal Government.



3.6 Subcontracted

Whether parts of tests for the product have been subcontracted to other labs:

☐ Yes ☒ No

If Yes, list the related test items and lab information:

Test items: ---

Lab information: ---

3.7 Abnormalities from Standard Conditions

None.

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4 Equipment Used during Test

☐ Mains Terminal Disturbance Voltage (Conducted Emission) 1#					
Item	Equipment	Manufacturer	Model No.	Serial No.	Calibration Status
1.	EMI Test Receiver	R&S	ESR3	102423	Valid
2.	LISN	R&S	ENV216	101343	Valid
3.	Cable	HUBER+SUHNER	CBL2-NN-6M	223NN624	Valid
4.	Switch	CD	RSU-A4	RSUA4008	Valid
☒ Mains Terminal Disturbance Voltage (Conducted Emission) 2#					
Item	Equipment	Manufacturer	Model No.	Serial No.	Calibration Status
1.	EMI Test Receiver	R&S	ESCI	101178	Valid
2.	LISN	R&S	ENV216	101215	Valid
3.	Cable 22	Times Microwave Systems	LMR195UF-BMNM-5.00M	---	Valid
4.	Switch	ESE	RSU/M2	---	Valid
☐ Mains Terminal Disturbance Voltage (Conducted Emission) 3#					
Item	Equipment	Manufacturer	Model No.	Serial No.	Calibration Status
1.	EMI Test Receiver	R&S	ESR3	102842	Valid
2.	LISN	R&S	ENV216	101542	Valid
3.	Cable 12	YIHENG	LMR195UF-NMNM-2.5	---	Valid
4.	Manual RF Switch	Top Precision	SW-2	RSU0402	Valid
☐ Radiated Emission (30MHz to 1GHz) 1#					
Item	Equipment	Manufacturer	Model No.	Serial No.	Calibration Status
1.	3m Semi-anechoic Chamber	CHANGCHUANG	9m×6m×6m	---	Valid
2.	EMI Test Receiver	R&S	ESR7	101566	Valid
3.	Trilog Broadband Antenna	SCHWARZBECK	VULB 9162	9162-117	Valid
4.	Cable 20	Times Microwave Systems	RG223-NMNM-10M	---	Valid
5.	Cable 21	Times Microwave Systems	RG223-NMNM-3M	---	Valid
☒ Radiated Emission (30MHz to 1GHz) 2#					
Item	Equipment	Manufacturer	Model No.	Serial No.	Calibration Status
1.	3m Semi-anechoic Chamber	YIHENG	9m×6m×6m	YH2021071801	Valid
2.	EMI Test Receiver	R&S	ESR7	102454	Valid
3.	Trilog Broadband Antenna	SCHWARZBECK	VULB 9163	01418	Valid
4.	Cable 14	YIHENG	LMR240UF-NMSM-7.5	---	Valid



☒ Radiated Emission (1GHz to 6GHz) 1#					
Item	Equipment	Manufacturer	Model No.	Serial No.	Calibration Status
1.	3m Semi-anechoic Chamber	CHANGCHUANG	9m×6m×6m	-	Valid
2.	EMI Test Receiver	R&S	ESR7	101566	Valid
3.	Broad-band Horn Antenna	SCHWARZBECK	BBHA 9120 D	01561	Valid
4.	Coaxial Cable (above 1GHz)	Times-Microwave	CBL5-NN	-	Valid
5.	Preamplifier	Lunar E M	LNA1G18-40	20160501002	Valid
☐ Radiated Emission (1GHz to 6GHz) 2#					
Item	Equipment	Manufacturer	Model No.	Serial No.	Calibration Status
1.	3m Semi-anechoic Chamber	CHANGCHUANG	9m×6m×6m	-	Valid
2.	EMI Test Receiver	R&S	ESR7	101566	Valid
3.	Broad-band Horn Antenna	SCHWARZBECK	BBHA 9120 D	01561	Valid
4.	Coaxial Cable (above 1GHz)	Times-Microwave	CBL5-NN	-	Valid
5.	Preamplifier	Lunar E M	LNA1G18-40	20160501002	Valid
☒ ESD					
Item	Equipment	Manufacturer	Model No.	Serial No.	Calibration Status
1.	ESD Simulator	TESEQ	NSG437	521	Valid
☒ EFT & Voltage Dips and Interruptions					
Item	Equipment	Manufacturer	Model No.	Serial No.	Calibration Status
1.	EMS test system	TESEQ	NSG3040	1858	Valid
2.	Step transformer	TESEQ	INA6501	206	Valid
3.	Coupling clamp	TESEQ	CDN8014	31405	Valid
☒ Surge					
Item	Equipment	Manufacturer	Model No.	Serial No.	Calibration Status
1.	Surge Simulator	TESEQ	NSG3060	1395	Valid
☒ Injected Currents					
Item	Equipment	Manufacturer	Model No.	Serial No.	Calibration Status
1.	Conducted Immunity test system	TESEQ	NSG4070	45345	Valid
2.	CDN	TESEQ	CDN M016	31586	Valid
3.	EM Clamp	TESEQ	KEMZ801	32362	Valid
4.	6dB Attenuator	TESEQ	ATN6075	32122	Valid



☒ Radio-frequency Electromagnetic Fields					
Item	Equipment	Manufacturer	Model No.	Serial No.	Calibration Status
1.	RF Power Amplifier	MICOTOP	MPA-80-1000-250	MPA2405139	Valid
2.	RF Power Amplifier	MICOTOP	MPA-1000-6000-100	MPA2405140	Valid
3.	Stacked double logarithmic periodic antenna	SCHWARZBECK	STLP9128E-SPECIAL	142	Valid
4.	Stacked double logarithmic periodic antenna	SCHWARZBECK	STLP 9149	476	Valid
5.	Analog signal generator	RS	SMB100A	105566	Valid
6.	Power meter	RS	NRP6A	101133	Valid
7.	Power meter	RS	NRP6A	101134	Valid

☐: Not Used

☒: Used

4.1 Software List

Description	Manufacturer	Model	Version
EMI Test Software (Conducted Emission 1#)	FARATRONIC	EZ-EMC	EMEC-3A1
EMI Test Software (Conducted Emission 2#)	FARATRONIC	EZ-CON	FARAD-3A1.1+
EMI Test Software (Conducted Emission 3#)	FARATRONIC	EZ-EMC	EMC-CON 3A1.1+
EMI Test Software (Radiated Emission 1#)	FARATRONIC	EZ-EMC	RA-03A1-2
EMI Test Software (Radiated Emission 2#)	FARATRONIC	EZ-EMC	RA-03A1-2
Radiated Immunity Test Software	Chinese EMC	EMS	V1.0.0.0

4.2 Measurement Uncertainty

Test Item	Frequency Range	Uncertainty	Note
Conducted Emission	150kHz~30MHz	±2.6dB	(1)
Radiated Emission	30MHz~1GHz	±4.5dB	(1)
Radiated Emission	1GHz~6GHz	±4.5dB	(1)

(1) This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of $k=2$.



4.3 Special Accessories and Auxiliary Equipment

Item	Equipment	Manufacturer	Model No.
1.	Notebook	Lenovo	ThinkPad Edge E430

4.4 Decision Rule

Compliance or non-compliance with a disturbance limit shall be determined in the following manner.

If U_{LAB} is less than or equal to U_{cispr} , then

- Compliance is deemed to occur if no measured disturbance level exceeds the disturbance limit;
- Non-compliance is deemed to occur if any measured disturbance level exceeds the disturbance limit.

If U_{LAB} is greater than U_{cispr} , then

- Compliance is deemed to occur if no measured disturbance level, increased by $(U_{LAB} - U_{cispr})$, exceeds the disturbance limit;
- Non-compliance is deemed to occur if any measured disturbance level, increased by $(U_{LAB} - U_{cispr})$, exceeds the disturbance limit.

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5 Emission Test Results

5.1 Mains Terminals Disturbance Voltage, 150 kHz to 30MHz

Test Requirement	: EN 55032 Annex A.3
Test Method	: EN 55032 Annex A.3
Limit	: Table A.10 of EN 55032
Test Result	: Pass
Frequency Range	: 150kHz to 30MHz
Class	: Class B

5.1.1 E.U.T. Operation

Operating Environment:

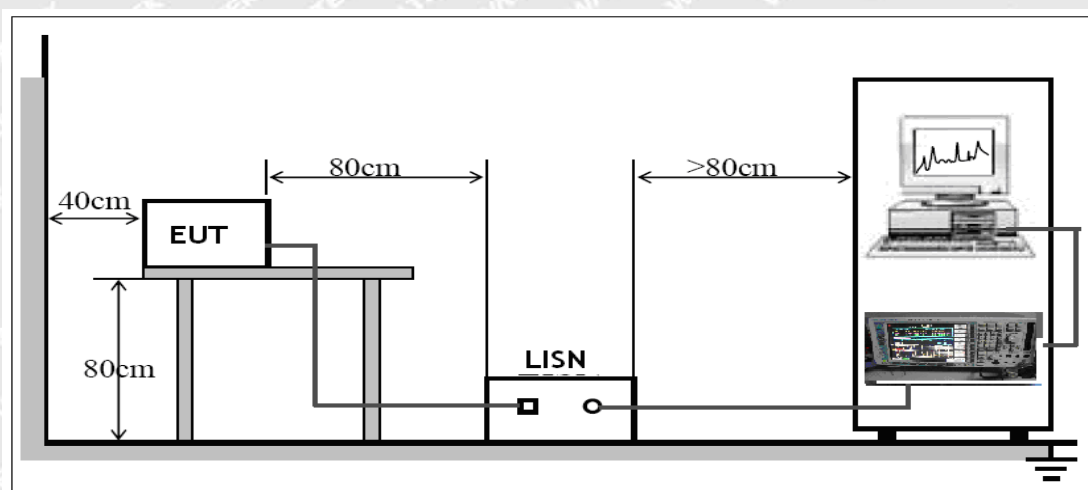
Temperature	: 20.8°C
Humidity	: 49.3%RH
Atmospheric Pressure	: 101.2kPa

EUT Operation:

Input Voltage	: Dongle: DC 5V (Notebook with AC 230V/50Hz input) Mouse: Battery 1.5V
Operating Mode	: Communication mode

5.1.2 Block Diagram of Test Setup

The Mains Terminals Disturbance Voltage tests were performed in accordance with the CISPR 16-1-2.



5.1.3 Measurement Data

The maximised peak emissions from the EUT was scanned and measured for both the Live and Neutral Lines. Quasi-peak & average measurements were performed if peak emissions were within 6dB of the average limit line.



5.1.4 Corrected Amplitude & Margin Calculation

The Corrected factor is calculated by adding LISN VDF(Voltage Division Factor), Cable Loss and Transient Limiter Attenuation. The basic equation is as follows:

$$\text{Measurement} = \text{Reading Level} + \text{Correct Factor}$$

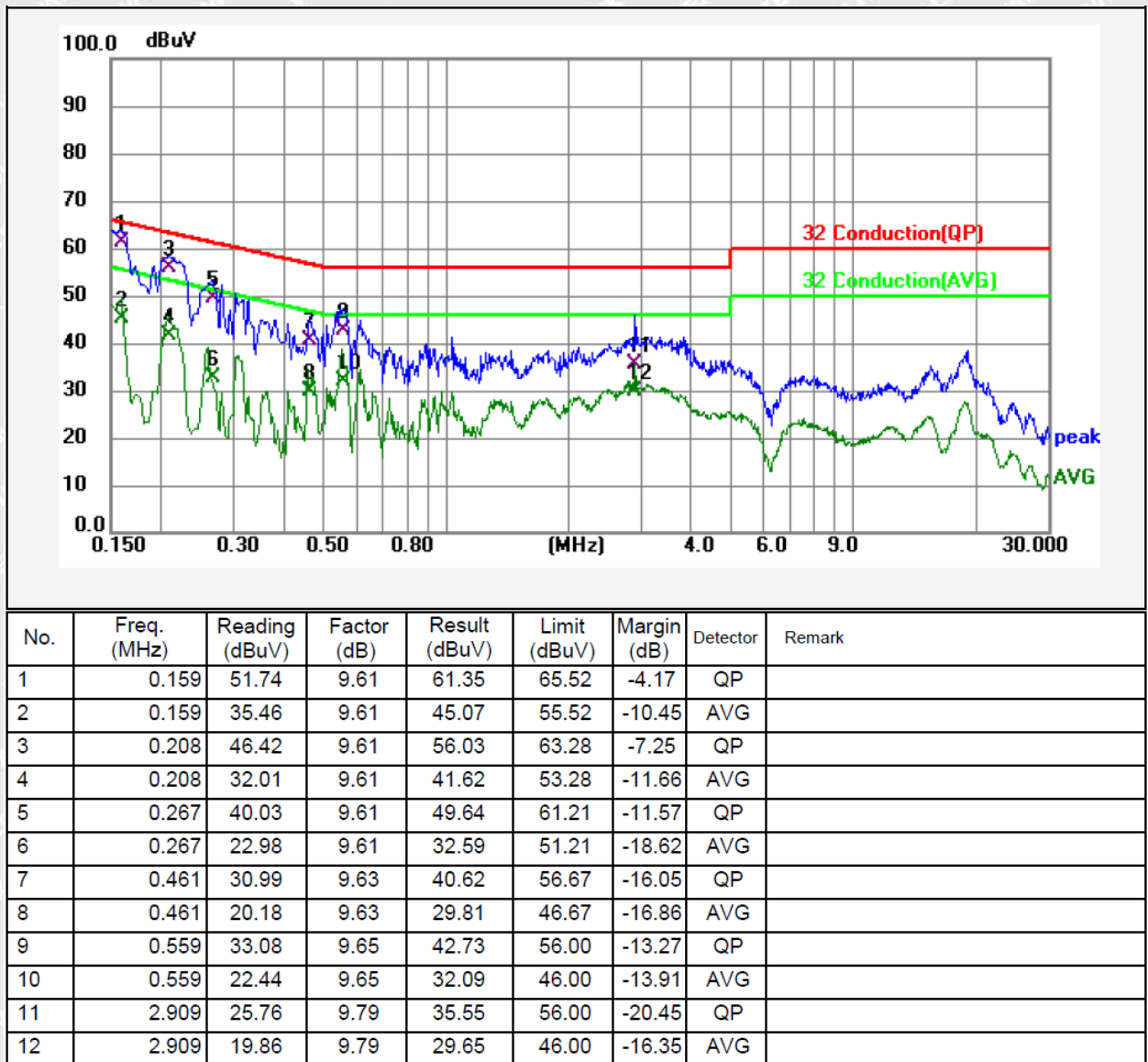
$$\text{Correct Factor} = \text{LISN VDF} + \text{Cable Loss}$$

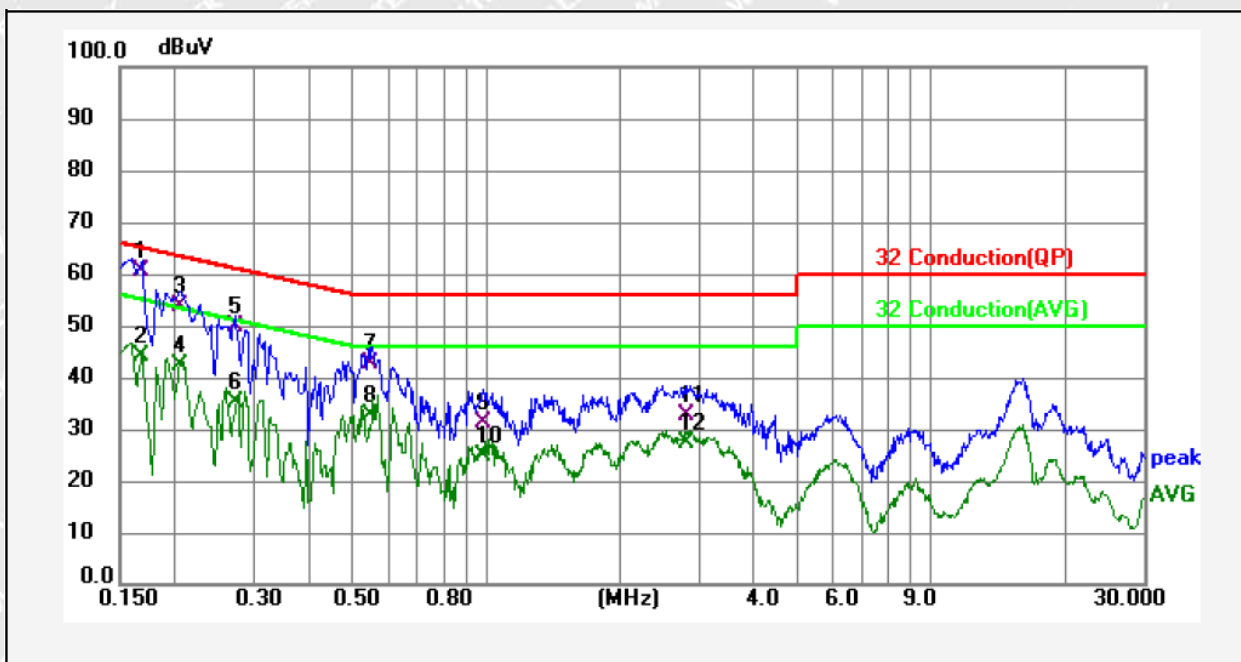
The "Margin" column of the following data tables indicates the degree of compliance with the applicable limit. For example, a margin of -7dB means the emission is 7dB below the limit. The equation for margin calculation is as follows:

$$\text{Margin} = \text{Measurement} - \text{Limit}$$

5.1.5 Mains Terminals Disturbance Voltage Test Data

Live Line



**Neutral Line**

No.	Freq. (MHz)	Reading (dBuV)	Factor (dB)	Result (dBuV)	Limit (dBuV)	Margin (dB)	Detector	Remark
1	0.168	50.98	9.53	60.51	65.06	-4.55	QP	
2	0.168	34.70	9.53	44.23	55.06	-10.83	AVG	
3	0.204	44.28	9.53	53.81	63.45	-9.64	QP	
4	0.204	32.77	9.53	42.30	53.45	-11.15	AVG	
5	0.272	40.36	9.54	49.90	61.06	-11.16	QP	
6	0.272	25.66	9.54	35.20	51.06	-15.86	AVG	
7	0.550	33.08	9.58	42.66	56.00	-13.34	QP	
8	0.550	23.12	9.58	32.70	46.00	-13.30	AVG	
9	0.983	21.76	9.60	31.36	56.00	-24.64	QP	
10	0.983	15.36	9.60	24.96	46.00	-21.04	AVG	
11	2.823	23.07	9.70	32.77	56.00	-23.23	QP	
12	2.823	17.69	9.70	27.39	46.00	-18.61	AVG	



5.2 Radiated Emission, 30MHz to 1GHz

Test Requirement	: EN 55032 Annex A.2
Test Method	: EN 55032 Annex A.2
Test Limit.....	: Table A.4 of EN 55032
Test Result	: Pass
Frequency Range	: 30MHz to 1000MHz
Class	: Class B

5.2.1 E.U.T. Operation

Operating Environment:

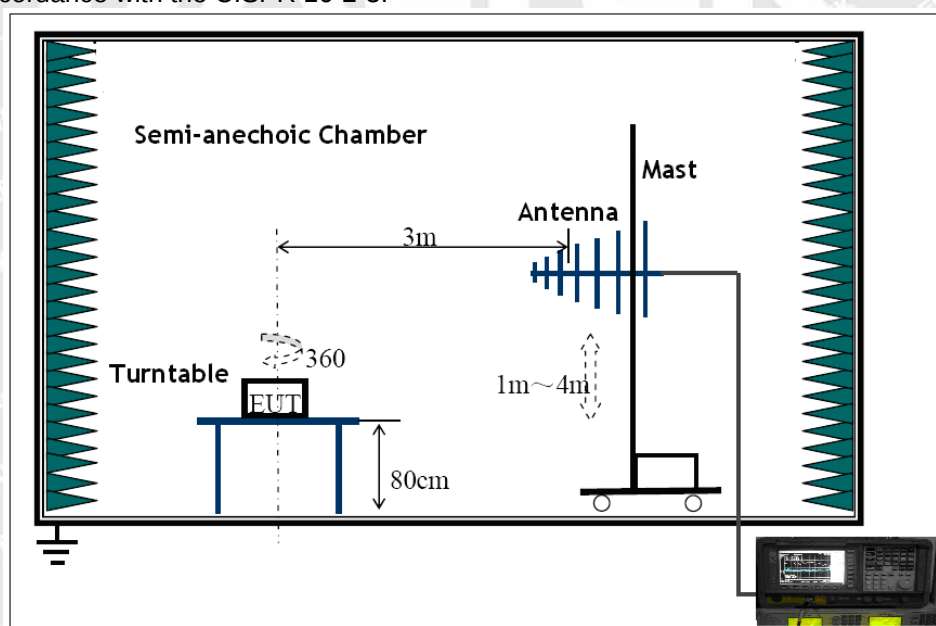
Temperature.....	: 22.6°C
Humidity	: 50.9%RH
Atmospheric Pressure	: 101.2kPa

EUT Operation:

Input Voltage.....	: Dongle: DC 5V (Notebook with AC 230V/50Hz input) Mouse: Battery 1.5V
Operating Mode	: Communication mode

5.2.2 Block Diagram of Test Setup

The Radiated Emission tests were performed in the 3m Semi- Anechoic Chamber test site, using the setup accordance with the CISPR 16-2-3.



5.2.3 Measurement Data

The maximised peak emissions from the EUT was scanned and measured for EUT 0°-360°. Quasi-peak measurements were performed if peak emissions were within 6dB of the limit line.



5.2.4 Corrected Amplitude & Margin Calculation

The Corrected Amplitude is calculated by adding the Antenna Factor and Cable Factor, and subtracting the Amplifier Gain from the Amplitude reading. The basic equation is as follows:

$$\text{Corr. Ampl.} = \text{Indicated Reading} + \text{Corr. Factor}$$

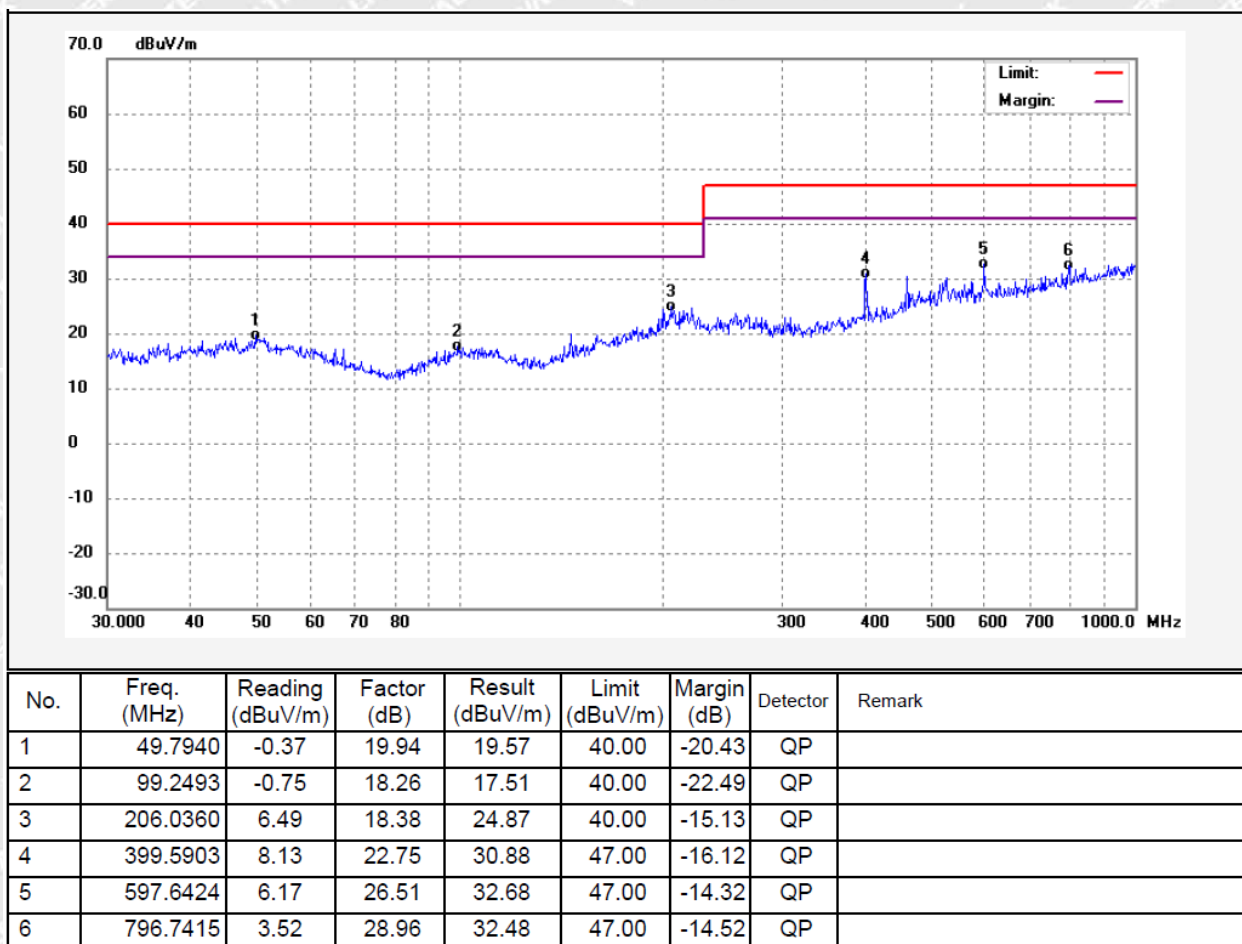
$$\text{Corr. Factor} = \text{Antenna Factor} + \text{Cable Factor} - \text{Amplifier Gain}$$

The "Margin" column of the following data tables indicates the degree of compliance with the applicable limit. For example, a margin of -7dB means the emission is 7dB below the maximum limit for Class B. The equation for margin calculation is as follows:

$$\text{Margin} = \text{Corr. Ampl.} - \text{Limit}$$

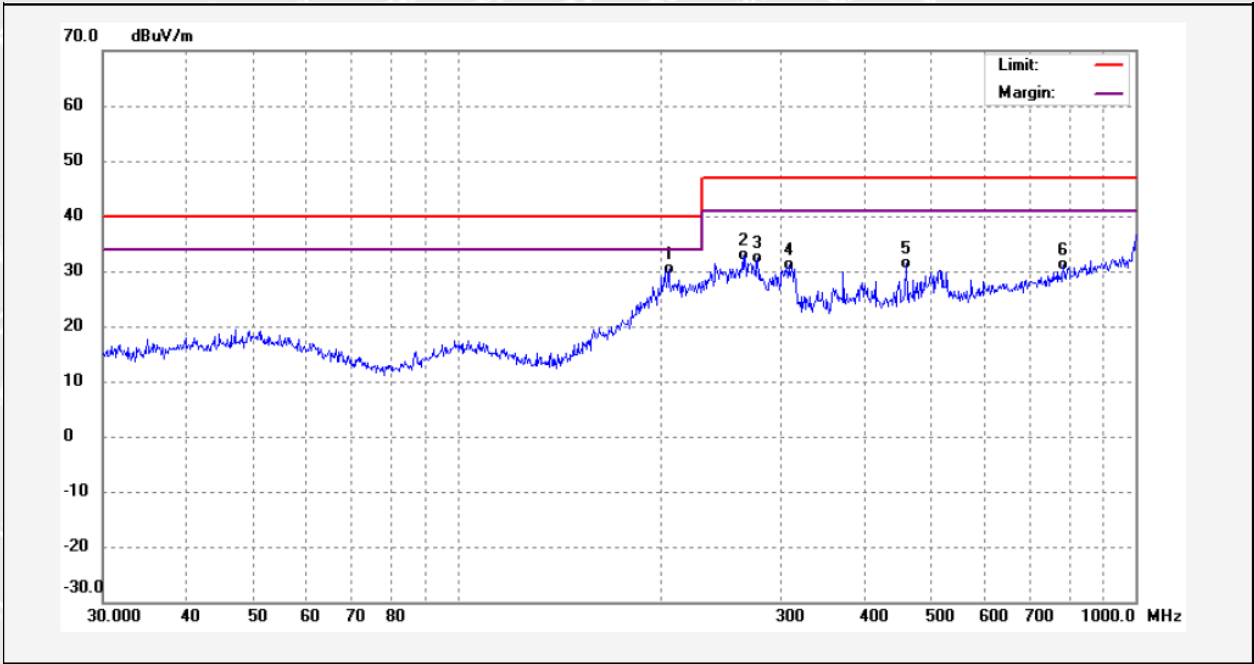
5.2.5 Radiated Emission Test Data

Vertical Polarization





Horizontal Polarization



No.	Freq. (MHz)	Reading (dBuV/m)	Factor (dB)	Result (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	Remark
1	205.4588	11.90	18.41	30.31	40.00	-9.69	QP	
2	264.7457	13.09	19.77	32.86	47.00	-14.14	QP	
3	277.8719	12.26	20.07	32.33	47.00	-14.67	QP	
4	308.5878	10.26	20.75	31.01	47.00	-15.99	QP	
5	460.0814	7.55	23.87	31.42	47.00	-15.58	QP	
6	783.7182	2.25	28.84	31.09	47.00	-15.91	QP	



5.3 Radiated Emission, 1GHz to 6GHz

Test Requirement	: EN 55032 Annex A.2
Test Method	: EN 55032 Annex A.2
Test Limit.....	: Table A.5 of EN 55032
Test Result	: Pass
Frequency Range	: 1GHz to 6GHz
Class.....	: Class B

5.3.1 E.U.T. Operation

Operating Environment:

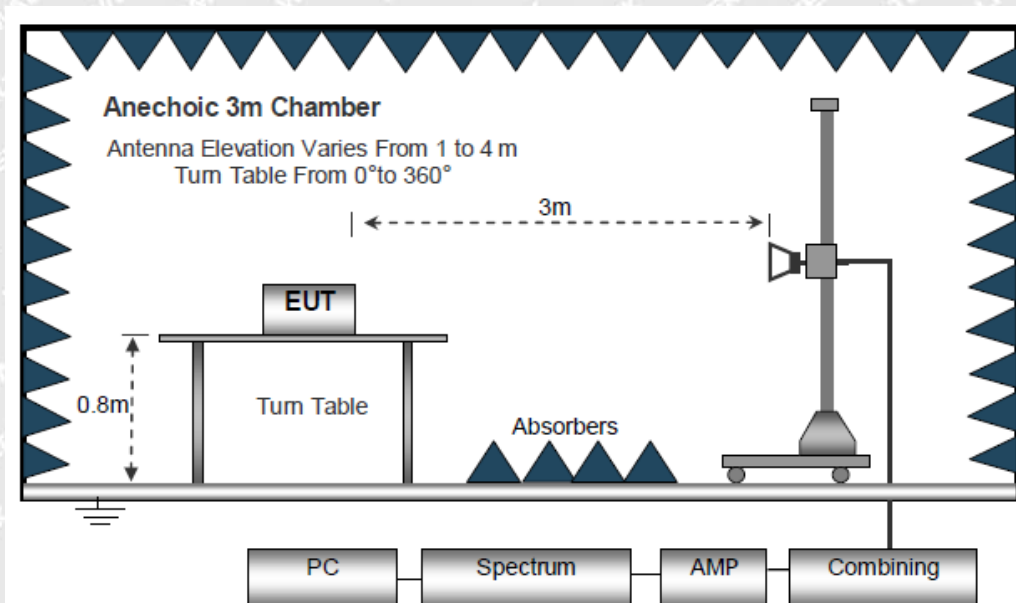
Temperature.....	: 22.6°C
Humidity	: 50.9%RH
Atmospheric Pressure	: 101.2kPa

EUT Operation:

Input Voltage.....	: Dongle: DC 5V (Notebook with AC 230V/50Hz input) Mouse: Battery 1.5V
Operating Mode	: Communication mode

5.3.2 Block Diagram of Test Setup

The Radiated Emission tests were performed in the 3m Semi- Anechoic Chamber test site, using the setup accordance with the CISPR 16-2-3.



5.3.3 Measurement Data

The maximised peak emissions from the EUT was scanned and measured for EUT 0°-360°. Quasi-peak measurements were performed if peak emissions were within 6dB of the limit line.



5.3.4 Corrected Amplitude & Margin Calculation

The Corrected Amplitude is calculated by adding the Antenna Factor and Cable Factor, and subtracting the Amplifier Gain from the Amplitude reading. The basic equation is as follows:

$$\text{Corr. Ampl.} = \text{Indicated Reading} + \text{Corr. Factor}$$

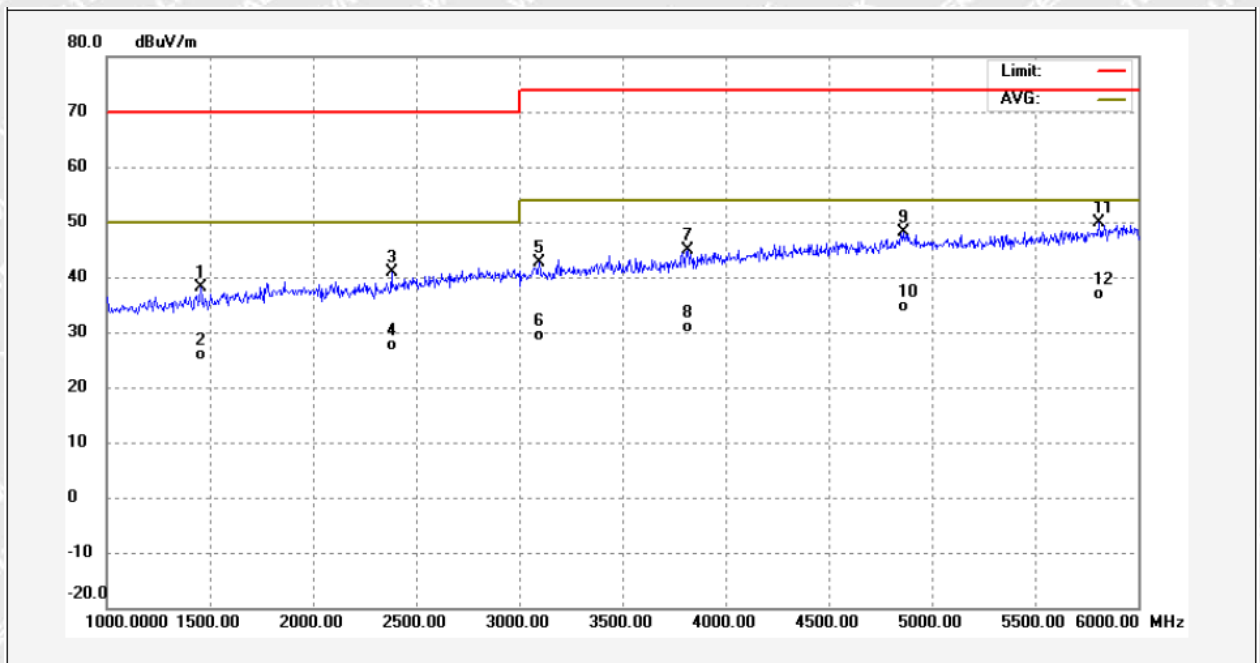
$$\text{Corr. Factor} = \text{Antenna Factor} + \text{Cable Factor} - \text{Amplifier Gain}$$

The "Margin" column of the following data tables indicates the degree of compliance with the applicable limit. For example, a margin of -7dB means the emission is 7dB below the maximum limit for Class B. The equation for margin calculation is as follows:

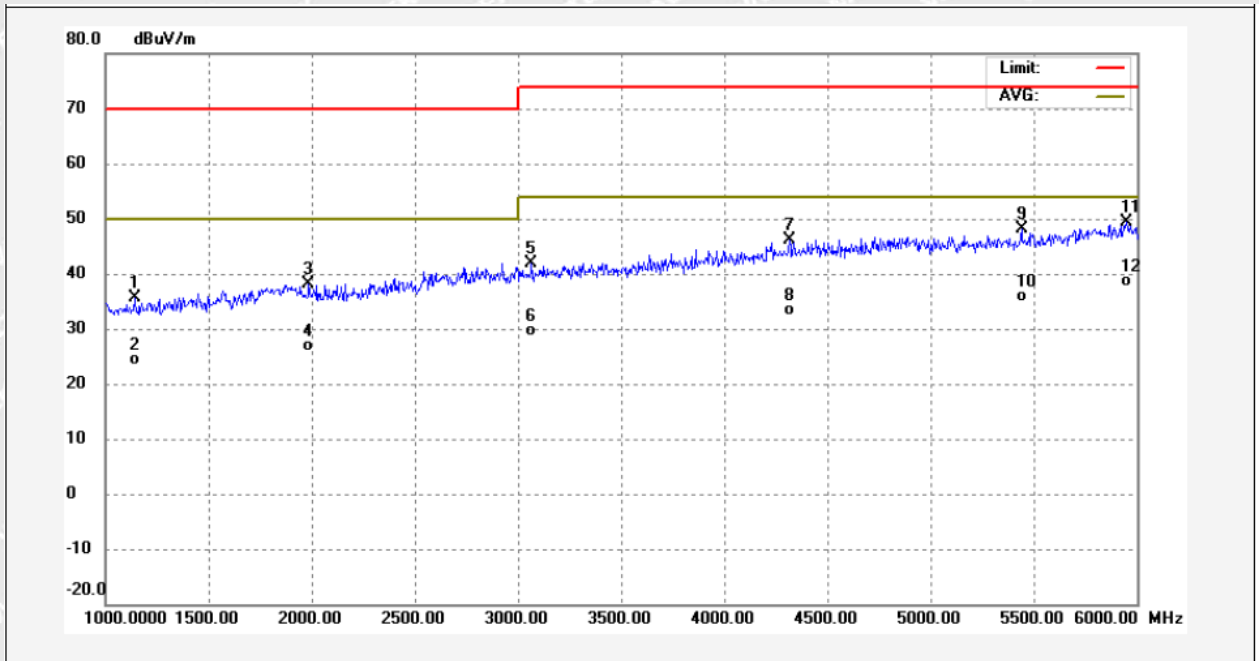
$$\text{Margin} = \text{Corr. Ampl.} - \text{Limit}$$

5.3.5 Radiated Emission Test Data

Vertical Polarization



No.	Freq. (MHz)	Reading (dBuV/m)	Factor (dB)	Result (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	Remark
1	1456.500	9.73	28.31	38.04	70.00	-31.96	peak	
2	1456.500	-2.43	28.31	25.88	50.00	-24.12	AVG	
3	2383.000	10.94	29.82	40.76	70.00	-29.24	peak	
4	2383.000	-2.18	29.82	27.64	50.00	-22.36	AVG	
5	3095.000	10.74	31.84	42.58	74.00	-31.42	peak	
6	3095.000	-2.53	31.84	29.31	54.00	-24.69	AVG	
7	3817.500	11.37	33.48	44.85	74.00	-29.15	peak	
8	3817.500	-2.58	33.48	30.90	54.00	-23.10	AVG	
9	4860.000	12.46	35.65	48.11	74.00	-25.89	peak	
10	4860.000	-0.99	35.65	34.66	54.00	-19.34	AVG	
11	5810.500	12.83	37.07	49.90	74.00	-24.10	peak	
12	5810.500	-0.23	37.07	36.84	54.00	-17.16	AVG	

**Horizontal Polarization**

No.	Freq. (MHz)	Reading (dBuV/m)	Factor (dB)	Result (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	Remark
1	1144.500	8.14	27.56	35.70	70.00	-34.30	peak	
2	1144.500	-3.26	27.56	24.30	50.00	-25.70	AVG	
3	1986.000	8.83	29.19	38.02	70.00	-31.98	peak	
4	1986.000	-2.42	29.19	26.77	50.00	-23.23	AVG	
5	3069.000	10.19	31.81	42.00	74.00	-32.00	peak	
6	3069.000	-2.12	31.81	29.69	54.00	-24.31	AVG	
7	4315.000	11.54	34.53	46.07	74.00	-27.93	peak	
8	4315.000	-1.25	34.53	33.28	54.00	-20.72	AVG	
9	5444.500	11.65	36.45	48.10	74.00	-25.90	peak	
10	5444.500	-0.65	36.45	35.80	54.00	-18.20	AVG	
11	5950.500	12.04	37.34	49.38	74.00	-24.62	peak	
12	5950.500	1.32	37.34	38.66	54.00	-15.34	AVG	



6 Immunity Test Results

6.1 Performance Criteria

Performance criterion A: The equipment shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer when the equipment is used as intended.

Performance criterion B: After the test, the equipment shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed, after the application of the phenomena below a performance level specified by the manufacturer, when the equipment is used as intended. During the test, degradation of performance is allowed. However, no change of operating state or stored data is allowed to persist after the test

Performance criterion C: Loss of function is allowed, provided the function is self-recoverable, or can be restored by the operation of the controls by the user in accordance with the manufacturer's instructions. Functions, and/or information stored in non-volatile memory, or protected by a battery backup, shall not be lost.

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6.2 Electrostatic Discharge (ESD)

Test Requirement	: EN 55035
Test Method	: IEC 61000-4-2
Test Result	: Pass
Discharge Impedance	: 330Ω / 150pF
Discharge Voltage	Air Discharge: ±8kV Contact Discharge: ±4kV HCP & VCP: ±4kV
Polarity	: Positive & Negative
Number of Discharge	: Minimum 10 times at each test point
Discharge Mode	: Single Discharge
Discharge Period	: 1 second minimum

6.2.1 E.U.T. Operation

Operating Environment:

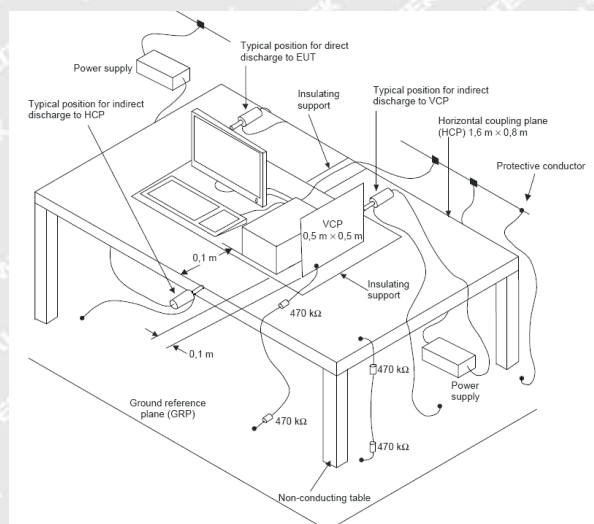
Temperature	: 22.6°C
Humidity	: 52.9%RH
Barometric Pressure	: 101.5kPa

EUT Operation:

Input Voltage	: Dongle: DC 5V (Notebook with AC 230V/50Hz input) Mouse: Battery 1.5V
Operating Mode	: Communication mode

6.2.2 Block Diagram of Setup

The ESD test was performed in accordance with the IEC 61000-4-2.





6.2.3 Direct Discharge Test Results

Observations:**Test points:**

1. All Exposed Surface & Seams;
2. All metallic part

Direct Discharge			Test Results	
Applied Voltage (kV)	Performance Criterion	Test Point	Contact Discharge	Air Discharge
±8	B	1	N/A	Pass*
±4	B	2	Pass*	N/A

Remark:

- * During the test no deviation was detected to the selected operation mode(s)

6.2.4 Indirect Discharge Test Results

Observations:**Test points:**

1. All sides.

Indirect Discharge			Test Results	
Applied Voltage (kV)	Performance Criterion	Test Point	Horizontal Coupling	Vertical Coupling
±4	B	1	Pass*	Pass*

Remark:

- * During the test no deviation was detected to the selected operation mode(s)



6.3 Continuous RF Electromagnetic Field Disturbances

Test Requirement	: EN 55035
Test Method	: IEC 61000-4-3
Test Result	: Pass
Frequency Range	: 80MHz to 1000MHz, 1800MHz, 2600MHz, 3500MHz, 5000MHz
Test level	: 3V/m
Modulation	: 80%, 1kHz Amplitude Modulation.
Face of EUT	: Front, Back, Left, Right
Antenna polarisation	: Horizontal & Vertical
Test Distance	: 3m

6.3.1 E.U.T. Operation

Operating Environment:

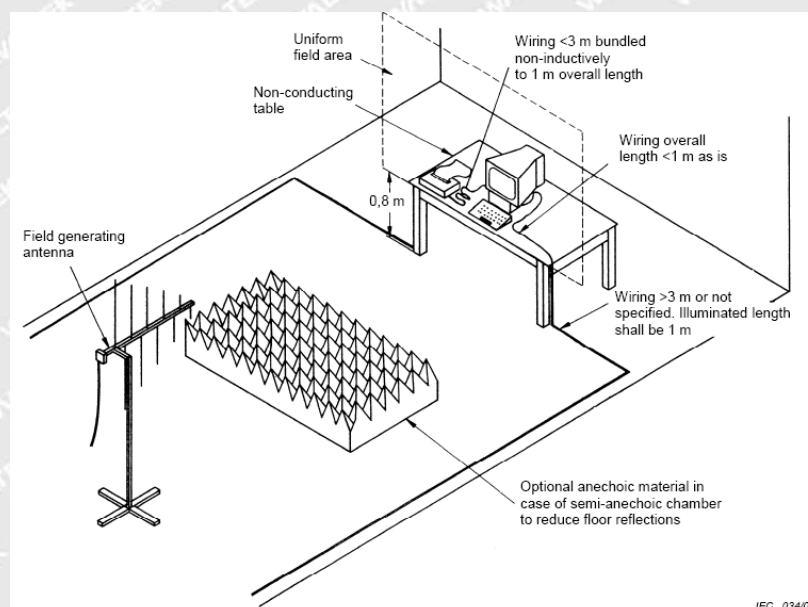
Temperature	: 23.1°C
Humidity	: 52.4%RH
Barometric Pressure	: 101.7kPa

EUT Operation:

Input Voltage	: Dongle: DC 5V (Notebook with AC 230V/50Hz input) Mouse: Battery 1.5V
Operating Mode	: Communication mode

6.3.2 Block Diagram of Setup

The Radio-frequency electromagnetic fields Immunity test was performed in accordance with the IEC 61000-4-3.





6.3.3 Test Results

Frequency	Face of EUT	Antenna polarisation	Test Level	Step Size	Dwell Time	Performance Criterion	Result
80 to 1000MHz	Front, Back, Left, Right	Horizontal	3V/m	1%	1s	A	Pass*
80 to 1000MHz	Front, Back, Left, Right	Vertical	3V/m	1%	1s	A	Pass*
1800MHz	Front, Back, Left, Right	Horizontal	3V/m	1%	1s	A	Pass*
1800MHz	Front, Back, Left, Right	Vertical	3V/m	1%	1s	A	Pass*
2600MHz	Front, Back, Left, Right	Horizontal	3V/m	1%	1s	A	Pass*
2600MHz	Front, Back, Left, Right	Vertical	3V/m	1%	1s	A	Pass*
3500MHz	Front, Back, Left, Right	Horizontal	3V/m	1%	1s	A	Pass*
3500MHz	Front, Back, Left, Right	Vertical	3V/m	1%	1s	A	Pass*
5000MHz	Front, Back, Left, Right	Horizontal	3V/m	1%	1s	A	Pass*
5000MHz	Front, Back, Left, Right	Vertical	3V/m	1%	1s	A	Pass*

Remark:

- * During the test no deviation was detected to the selected operation mode(s)



6.4 Electrical Fast Transients (EFT)

Test Requirement : EN 55035
Test Method : IEC 61000-4-4
Test Result : Pass
Test Level : 1.0kV on AC Mains
Polarity : Positive & Negative
Repetition Frequency : 5kHz
Burst Duration : 5/50ns
Test Duration : 2 minutes per level & polarity

6.4.1E.U.T. Operation

Operating Environment:

Temperature : 22.6°C
Humidity : 52.8%RH
Barometric Pressure : 101.5kPa

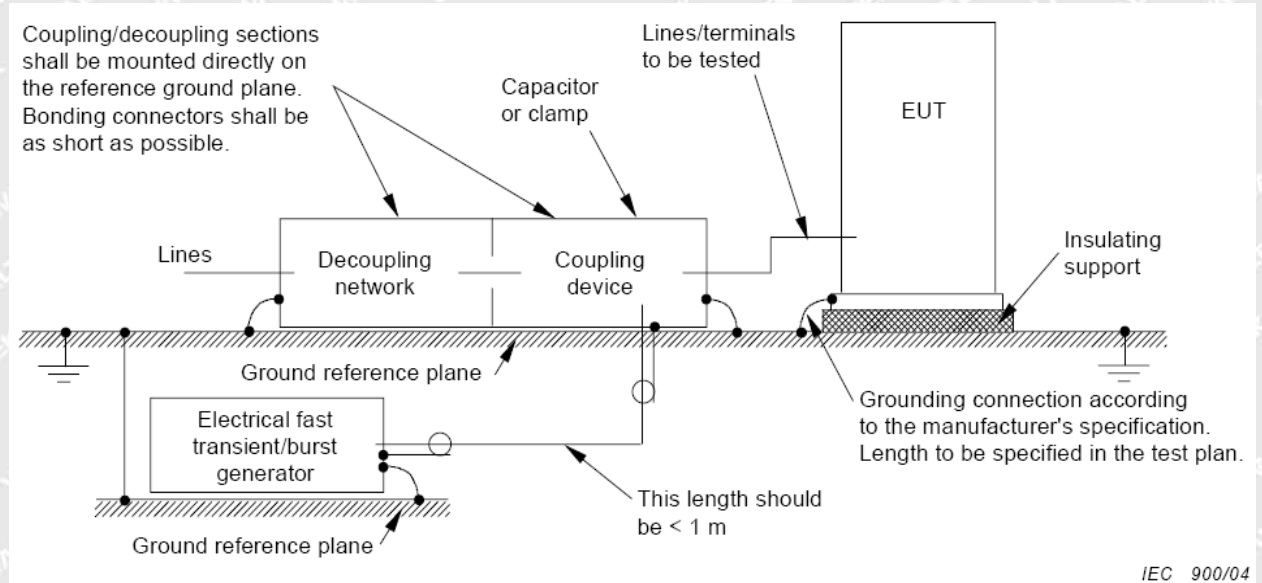
EUT Operation:

Input Voltage : Dongle: DC 5V (Notebook with AC 230V/50Hz input)
Mouse: Battery 1.5V
Operating Mode : Communication mode



6.4.2 Block Diagram of Setup

The Electrical Fast Transients Immunity test was performed in accordance with the IEC 61000-4-4.



6.4.3 Test Results

Test Port	Test Level(kV)	Performance Criterion	Result
Line-Neutral	± 1.0	B	Pass*

Remark:

* During the test no deviation was detected to the selected operation mode(s)



6.5 Surge

Test Requirement : EN 55035

Test Method : IEC 61000-4-5

Test Result : Pass

Test level : $\pm 1\text{kV}$ Live to Neutral, $\pm 2\text{kV}$ Live to PE and Neutral to PE

Interval : 60s between each surge

No. of surges : five positive and five negative pulses each at 0° , 90° , 180° and at 270°

6.5.1E.U.T. Operation

Operating Environment:

Temperature : 23.0°C

Humidity : 52.8%RH

Barometric Pressure : 101.6kPa

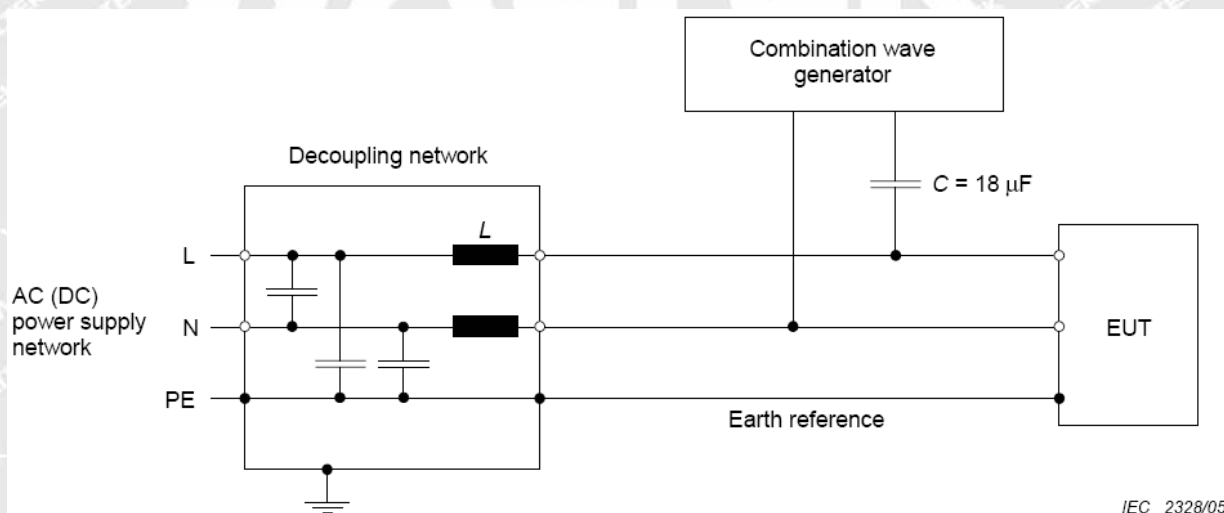
EUT Operation:

Input Voltage : Dongle: DC 5V (Notebook with AC 230V/50Hz input)
Mouse: Battery 1.5V

Operating Mode : Communication mode

6.5.2Block Diagram of Setup

The Surge Immunity test was performed in accordance with the IEC 61000-4-5.





6.5.3 Test Result

Test Port	Applied Voltage (kV)	Performance criterion	Result
Between Phase And Phase	± 1	B	N/A
Between Live And Neutral	± 1	B	Pass*
Between Live And Earth	± 2	B	N/A
Between Neutral And Earth	± 2	B	N/A

Remark:

- * During the test no deviation was detected to the selected operation mode(s)

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6.6 Continuous Induced RF Disturbance

Test Requirement : EN 55035

Test Method : IEC 61000-4-6

Test Result : Pass

Frequency Range : 0.15 to 10MHz, 10 to 30MHz, 30 to 80MHz

Test level : 3V r.m.s. / 3~1V r.m.s. / 1V r.m.s. (unmodulated emf into 150 Ω)

Modulation : 80%, 1kHz Amplitude Modulation.

6.6.1E.U.T. Operation

Operating Environment:

Temperature : 22.6°C

Humidity : 53.0%RH

Barometric Pressure : 101.5kPa

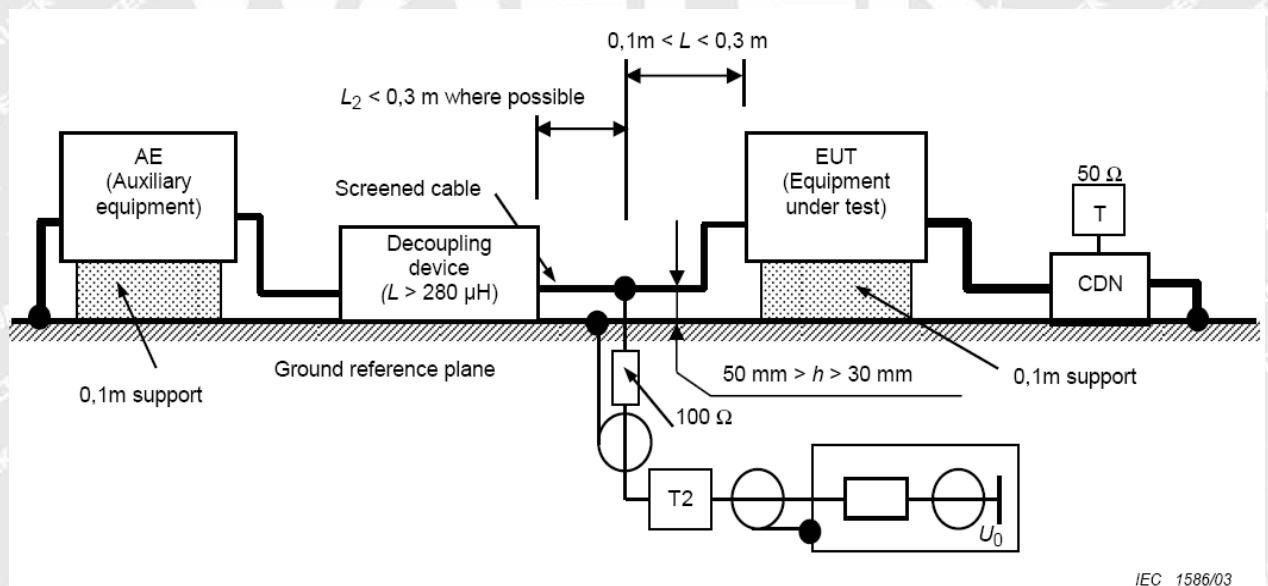
EUT Operation:

Input Voltage : Dongle: DC 5V (Notebook with AC 230V/50Hz input)
Mouse: Battery 1.5V

Operating Mode : Communication mode

6.6.2 Block Diagram of Setup

The Injected Currents Immunity test was performed in accordance with the IEC 61000-4-6.





6.6.3Test Results

Frequency	Line	Test Level	Modulation	Step Size	Dwell Time	Performance Criterion	Result
0.15MHz to 10MHz	2 Wire AC Supply Cables	3Vr.m.s.	80%, 1kHz Amp. Mod.	1%	1s	A	Pass*
10MHz to 30MHz	2 Wire AC Supply Cables	3 to 1 Vr.m.s.	80%, 1kHz Amp. Mod.	1%	1s	A	Pass*
30MHz to 80MHz	2 Wire AC Supply Cables	1Vr.m.s.	80%, 1kHz Amp. Mod.	1%	1s	A	Pass*

Remark:
* During the test no deviation was detected to the selected operation mode(s)

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6.7 Voltage Dips and Interruptions

Test Requirement	: EN 55035
Test Method	: IEC 61000-4-11
Test Result	: Pass
Test Level(Voltage reduction)	: >90% & 30 % of Induction
No. of Dips / Interruptions	: 1 per Level at 20ms intervals

6.7.1E.U.T. Operation

Operating Environment:

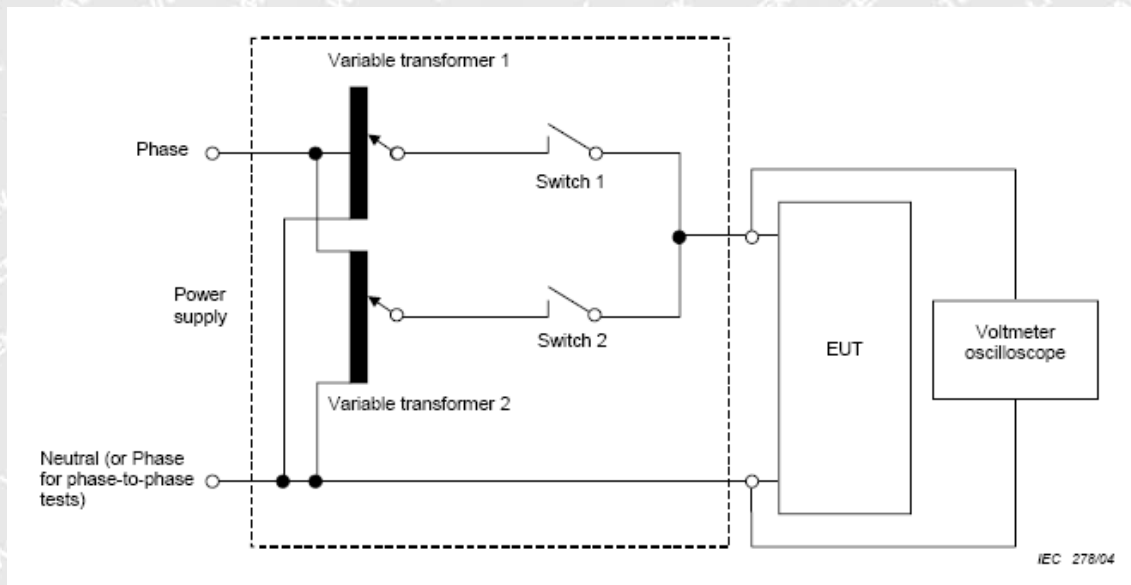
Temperature	: 22.5°C
Humidity	: 52.7%RH
Barometric Pressure	: 101.6kPa

EUT Operation:

Input Voltage	: Dongle: DC 5V (Notebook with AC 230V/50Hz input) Mouse: Battery 1.5V
Operating Mode	: Communication mode

6.7.2 Block Diagram of Setup

The Voltage Dips and Interruptions Immunity test was performed in accordance with the IEC 61000-4-11.





6.7.3Test Results

Test Item	Test Level in %U _T	Performance criterion	50Hz		60Hz	
			Duration	Result	Duration	Result
Voltage Dips	< 5	B	0.5	Pass*	0.5	N/A
	70	C	25	Pass*	30	N/A
Voltage Interruptions	< 5	C	250	Pass*	300	N/A

Remark:

* During the test no deviation was detected to the selected operation mode(s)

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7 Photographs – Test Setup

7.1 Photograph – Mains Terminal Disturbance Voltage Test Setup



7.2 Photograph – Radiated Emission Test Setup, 30MHz to 1GHz





7.3 Photograph – Radiated Emission Test Setup, 1GHz to 6GHz



7.4 Photograph – ESD Immunity Test Setup





7.5 Photograph – Continuous RF Electromagnetic Field Disturbances Test Setup



7.6 Photograph – EFT Immunity Test Setup





7.7 Photograph – Surge Immunity Test Setup



7.8 Photograph – Continuous Induced RF Disturbance Test Setup





7.9 Photograph – Voltage Dips and Interruptions Immunity Test Setup



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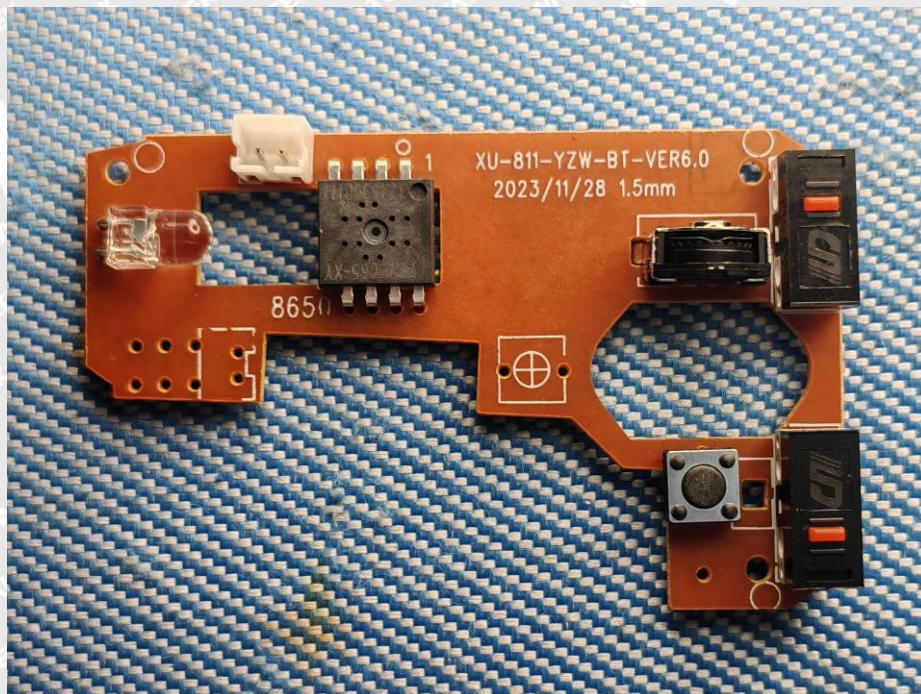
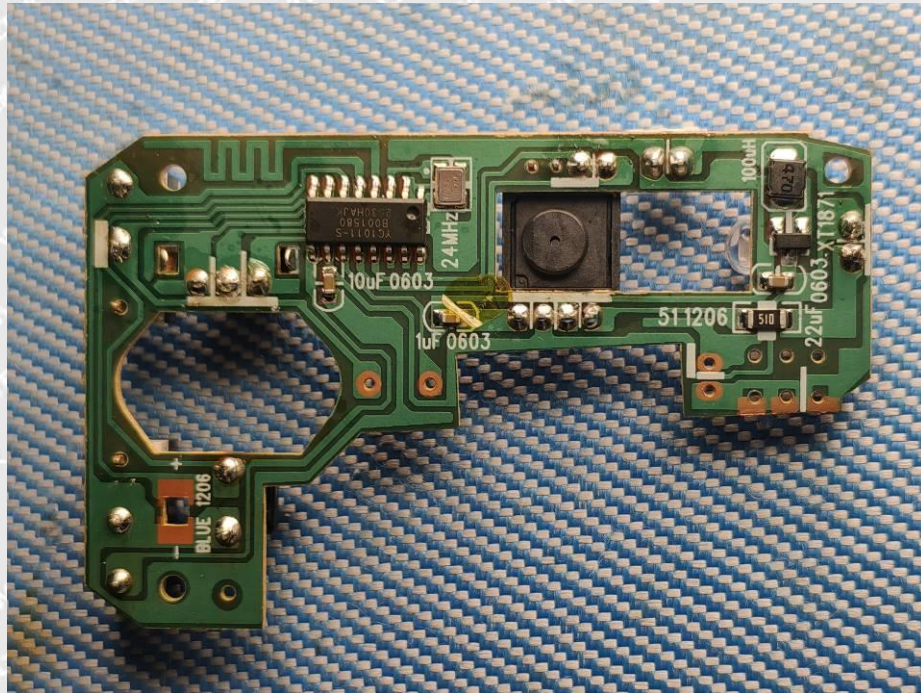
8 Photographs – Constructional Details

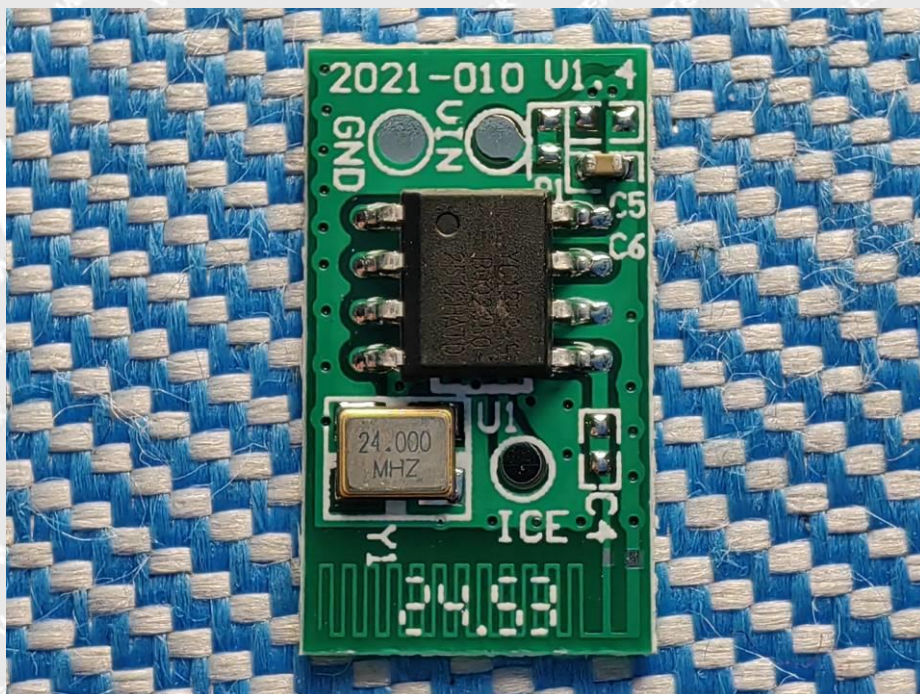
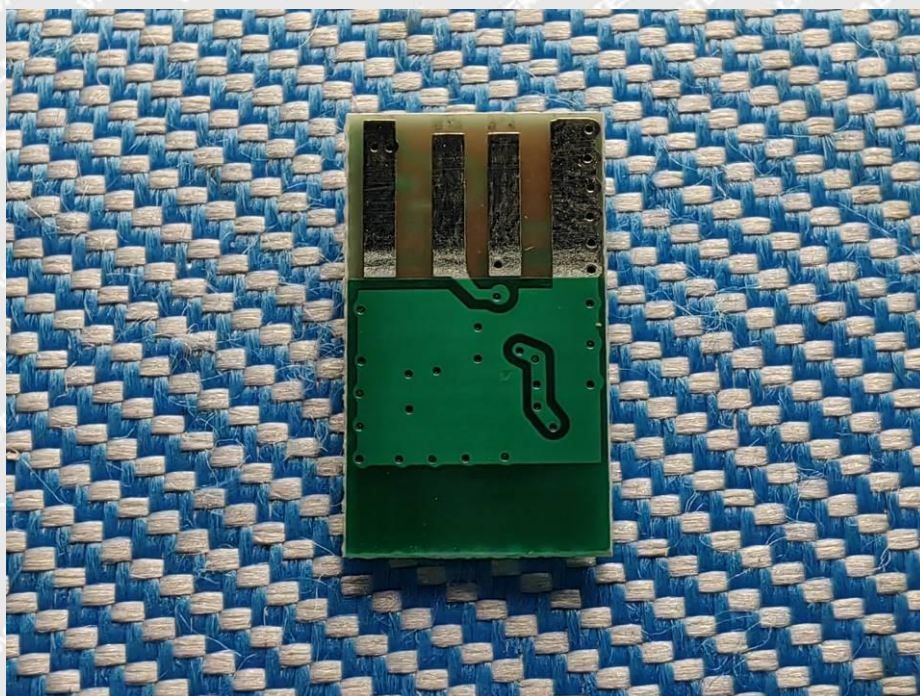
8.1 EUT – External Photos





8.2 EUT – External Photos





===== End of Report =====